SAR Test Report

For

Applicant Name:	**ThinkRace Technology Co., Limited**
Address:	21/F Hing Lung Commercial Building 68-74 Bonham Strand East Sheung Wan Hongkong
EUT Name:	Ankle Tracker
Brand Name:	Traxbean
Model Number:	TR40
Series Model Number:	Refer to section 2

Issued By

Company Name:	**BTF Testing Lab (Shenzhen) Co., Ltd.**
Address:	F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China
Report Number:	BTF230922R00101
Test Standards:	47 CFR Part 2.1093 IEEE1528-2013 IEEE C95.1-2019 KDB447498 D01 KDB865664 D01 KDB865664 D02 KDB941225 D05 KDB690783 D01
FCC ID:	2BCJQ-TR40
Test Conclusion:	Pass
Test Date:	2023-09-25
Date of Issue:	2023-09-27
Prepared By:	Monica Zhou / Project Engineer
Date:	2023-09-27
Approved By:	Ryan.CJ / EMC Manager
Date:	2023-09-27

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Revision History		
Version	Issue Date	Revisions Content
R_V0	2023-09-27	Original
Note:	*Once the revision has been made, then previous versions reports are invalid.*	

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1. Introduction

1.1 Identification of Testing Laboratory

Company Name:	BTF Testing Lab (Shenzhen) Co., Ltd.
Address:	F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China
Phone Number:	+86-0755-23146130
Fax Number:	+86-0755-23146130

1.2 Identification of the Responsible Testing Location

Test Location:	BTF Testing Lab (Shenzhen) Co., Ltd.
Address:	F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China
Description:	All measurement facilities used to collect the measurement data are located at F101,201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China
FCC Registration Number	518915
Designation Number	CN1330

1.3 Laboratory Condition

Ambient Temperature:	21℃ to 25℃
Ambient Relative Humidity:	48% to 59%
Ambient Pressure:	100 kPa to 102 kPa

1.4 Announcement

(1) The test report reference to the report template version v0.

(2) The test report is invalid if not marked with the signatures of the persons responsible for preparing, reviewing and approving the test report.

(3) The test report is invalid if there is any evidence and/or falsification.

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2. Product Information

2.1 Application Information

Company Name:	ThinkRace Technology Co., Limited
Address:	21/F Hing Lung Commercial Building 68-74 Bonham Strand East Sheung Wan Hongkong

2.2 Manufacturer Information

Company Name:	Shenzhen Guanaixing Technology Co., Ltd
Address:	201-A090, Block B, Huayuancheng Digital Building, 1079 Nanhai Avenue, Yanshan Community, Nanshan District, Shenzhen, China

2.3 Factory Information

Company Name:	Shenzhen Guanaixing Technology Co., Ltd.
Address:	201-A090, Block B, Huayuancheng Digital Building, 1079 Nanhai Avenue, Yanshan Community, Nanshan District, Shenzhen, China

2.4 General Description of Equipment under Test (EUT)

EUT Name	Ankle Tracker
Under Test Model Name	TR40
Series Model Name	TR50, TR60, TR70, TR80
Description of Model name differentiation	Only the model name is different, others are the same.
Sample No.	BTFSN230922001-1/1

2.5 Equipment under Test Ancillary Equipment

Ancillary Equipment 1	Rechargeable Li-ion Battery	
	Capacity	1400mAh
	Rated Voltage	3.8V

2.6 Technical Information

Network and Wireless connectivity	2G Network GSM 850/1900 4G Network FDD LTE Band 2/4/5/7/12/17 BT (EDR)

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The requirement for the following technical information of the EUT was tested in this report:

Operating Mode	GSM, LTE, Bluetooth		
Frequency Range	GSM 850	TX: 824 ~ 849 MHz	RX: 869 ~ 894 MHz
	GSM 1900	TX: 1850 ~ 1910 MHz	RX: 1930 ~ 1990 MHz
	LTE Band 2	Tx: 1850 ~ 1910 MHz	Rx: 1930 ~ 1990 MHz
	LTE Band 4	Tx: 1710 ~ 1755 MHz	Rx: 2110 ~ 2155 MHz
	LTE Band 5	TX: 824 ~ 849 MHz	RX: 869 ~ 894 MHz
	LTE Band 7	TX: 2500 ~ 2570 MHz	RX: 2620 ~ 2690 MHz
	LTE Band 12	TX: 698 ~ 716 MHz	RX: 728 ~ 746 MHz
	LTE Band 17	TX: 704 ~ 716 MHz	RX: 734 ~ 746 MHz
	Bluetooth	2402 ~ 2480 MHz	
Antenna Type	WWAN: FPC Antenna BT: FPC Antenna		
Hotspot Function	Not Support		
Power Reduction	Not Support		
Exposure Category	General Population/Uncontrolled exposure		
EUT Stage	Portable Device		
Product	Type		
	☐ Production unit	☒ Identical prototype	

3. Summary of Test Results

3.1 Test Standards

No.	Identity	Document Title
1	47 CFR Part 2.1093	Radiofrequency radiation exposure evaluation: portable devices
2	IEEE1528-2013	Recommended Practice for Determining the Peak Spatial-Average Specific Absorption Rate in the Human Head from Wireless Communications Devices: Measurement Techniques
3	IEEE C95.1-2019	IEEE Standard for Safety Levels with Respect to Human Exposure to Electric, Magnetic, and Electromagnetic Fields, 0 Hz to 300 GHz
4	KDB447498 D01	General RF Exposure Guidance v06
5	KDB865664 D01	SAR measurement 100MHz to 6GHz v01r04
6	KDB865664 D02	RF Exposure Reporting v01r02
7	KDB941225 D05	SAR for LTE Devices v02r05
8	KDB690783 D01	SAR Listings on Grant v01r03

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3.2 Device Category and SAR Limit

This device belongs to portable device category because its radiating structure is allowed to be used within 20 centimeters of the body of the user. Limit for General Population/Uncontrolled exposure should be applied for this device, it is 1.6 W/kg as averaged over any 1 gram of tissue.

Body Position	SAR Value (W/Kg)	
	General Population/ Uncontrolled Exposure	Occupational/ Controlled Exposure
Whole-Body SAR (averaged over the entire body)	0.08	0.4
Partial-Body SAR (averaged over any 1 gram of tissue)	1.60	8.0
SAR for hands, wrists, feet and ankles (averaged over any 10 grams of tissue)	4.0	20.0

NOTE:
General Population/Uncontrolled Exposure: Locations where there is the exposure of individuals who have no knowledge or control of their exposure. General population/uncontrolled exposure limits are applicable to situations in which the general public may be exposed or in which persons who are exposed as a consequence of their employment may not be made fully aware of the potential for exposure or cannot exercise control over their exposure. Members of the general public would come under this category when exposure is not employment- related; for example, in the case of a wireless transmitter that exposes persons in its vicinity.

Occupational/Controlled Exposure: Locations where there is exposure that may be incurred by persons who are aware of the potential for exposure, In general, occupational/controlled exposure limits are applicable to situations in which persons are exposed as a consequence of their employment, who have been made fully aware of the potential for exposure and can exercise control over their exposure. This exposure category is also applicable when the exposure is of a transient nature due to incidental passage through a location where the exposure levels may be higher than the general population/uncontrolled limits, but the exposed person is fully aware of the potential for exposure and can exercise control over his or her exposure by leaving the area or by some other appropriate means.

3.3 Test Result Summary

The maximum results of Specific Absorption Rate (SAR) found during test as bellows:

<Highest Reported standalone SAR Summary>

Frequency Band		Maximum Reported SAR (W/kg) 10 g
		Extremity SAR (Separation 0 mm)
WWAN	GSM 850	0.256
	GSM 1900	0.175
	LTE FDD Band 2	0.124
	LTE FDD Band 4	0.113
	LTE FDD Band 5	0.132
	LTE FDD Band 7	0.176
	LTE FDD Band 12	0.050
	LTE FDD Band 17	0.041
Limits (W/kg)		4.0
Test Verdict		Pass

This device is in compliance with Specific Absorption Rate(SAR) for general population/uncontrolled exposure limits (4.0 W/kg) specified in FCC47 CFR part 2(2.1093) and ANSI/IEEE C95.1-2019, and had been tested in accordance with the measurement methods and procedures specified in IEEE 1528-2013.

<Maximum Reported Simultaneous SAR>

Exposure Position	Simultaneous Configuration	Maximum Reported Simultaneous Transmission SAR (W/kg)	Limit (W/kg)	Verdict
Extremity 10g SAR (0mm Gap)	GSM 850 + BT	0.289	4.0	Pass

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3.4 Test Uncertainty

3.4.1 Measurement uncertainly evaluation for SAR test

Measurement uncertainly evaluation for SAR test (300MHz to 6GHz)

Uncertainty Component	Tol (+- %)	Prob. Dist.	Div.	Ci (1g)	Ci (10g)	1g Ui (+- %)	10 g Ui (+-%)	Vi veff
Measurement System								
Probe calibration	5.8	N	1	1	1	5.80	5.80	∞
Axial Isotropy	3.5	R	√3	√0.5	√0.5	1.43	1.43	∞
Hemispherical Isotropy	5.9	R	√3	√0.5	√0.5	2.41	2.41	∞
Boundary effect	1.0	R	√3	1	1	0.58	0.58	∞
Linearity	4.7	R	√3	1	1	2.71	2.71	∞
System detection limits	1.0	R	√3	1	1	0.58	0.58	∞
Modulation response	3.0	R	√3	1	1	1.73	1.73	∞
Readout Electronics	0.5	N	1	1	1	0.50	0.50	∞
Response Time	0	R	√3	1	1	0.00	0.00	∞
Integration Time	1.4	R	√3	1	1	0.81	0.81	∞
RF ambient Conditions - Noise	3.0	R	√3	1	1	1.73	1.73	∞
RF ambient Conditions - Reflections	3.0	R	√3	1	1	1.73	1.73	∞
Probe positioner Mechanical Tolerance	1.4	R	√3	1	1	0.81	0.81	∞
Probe positioning with respect to Phantom Shell	1.4	R	√3	1	1	0.81	0.81	∞
Extrapolation, interpolation and integration Algorithms for Max. SAR Evaluation	2.3	R	√3	1	1	1.33	1.33	∞
Test sample Related								
Test sample positioning	2.6	N	1	1	1	2.60	2.60	11
Device Holder Uncertainty	3.0	N	1	1	1	3.00	3.00	7
Output power Variation - SAR drift measurement	5.0	R	√3	1	1	2.89	2.89	∞
SAR scaling	2.0	R	√3	1	1	1.15	1.15	∞
Phantom and Tissue Parameters								
Phantom Shell Uncertainty - Shape,Thickness and Permittivity	4	R	√3	1	1	2.31	2.31	∞
Uncertainty in SAR correction for deviation in permittivity and conductivity	2.0	N	1	1	0.84	2.00	1.68	∞
Liquid conductivity measurement	4.0	N	1	0.78	0.71	3.12	2.84	5
Liquid permittivity measurement	5.0	N	1	0.23	0.26	1.15	1.30	5
Liquid Conductivity - Temperature Uncertainty	2.5	R	√3	0.78	0.71	1.13	1.02	∞
Liquid permittivity - Temperature Uncertainty	2.5	R	√3	0.23	0.26	0.33	0.38	∞
Combined Standard Uncertainty		RSS				10.47	10.34	
Expanded Uncertainty (95% Confidence interval)		k				20.95	20.69	

* This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

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3.4.2 Measurement uncertainly evaluation for system check

Uncertainty Component	Tol (+- %)	Prob. Dist.	Div.	Ci (1g)	Ci (10 g)	1g Ui (+-%)	10 g Ui (+-%)	Vi veff
Measurement System								
Probe calibration	5.8	N	1	1	1	5.80	5.80	∞
Axial Isotropy	3.5	R	√3	1	1	2.02	2.02	∞
Hemispherical Isotropy	5.9	R	√3	0	0	0.00	0.00	∞
Boundary effect	1	R	√3	1	1	0.58	0.58	∞
Linearity	4.7	R	√3	1	1	2.71	2.71	∞
System detection limits	1	R	√3	1	1	0.58	0.58	∞
Modulation response	0	N	√3	0	0	0.00	0.00	∞
Readout Electronics	0.5	N	1	1	1	0.50	0.50	∞
Response Time	0	R	√3	0	0	0.00	0.00	∞
Integration Time	1.4	R	√3	0	0	0.00	0.00	∞
RF ambient Conditions - Noise	3	R	√3	1	1	1.73	1.73	∞
RF ambient Conditions - Reflections	3	R	√3	1	1	1.73	1.73	∞
Probe positioner Mechanical Tolerance	1.4	R	√3	1	1	0.81	0.81	∞
Probe positioning with respect to Phantom Shell	1.4	R	√3	1	1	0.81	0.81	∞
Extrapolation, interpolation and integration Algorithms for Max. SAR Evaluation	2.3	R	√3	1	1	1.33	1.33	∞
Dipole								
Deviation of experimental source from numerical source	5	N	1	1	1	5.00	5.00	∞
Input Power and SAR driftmeasurement	0.5	R	√3	1	1	0.29	0.29	∞
Dipole Axis to Liquid Dist.	2.0	R	√3	1	1	1.15	1.15	∞
Phantom and Tissue Parameters								
Phantom Shell Uncertainty - Shape,Thickness and Permittivity	4	R	√3	1	1	2.31	2.31	∞
Uncertainty in SAR correction for deviation in permittivity and conductivity	2.0	N	1	1	0.84	2.00	1.68	∞
Liquid conductivity measurement	4	N	1	0.78	0.71	3.12	2.84	5
Liquid permittivity measurement	5.0	N	1	0.23	0.26	1.15	1.30	5
Liquid Conductivity - Temperature Uncertainty	2.5	R	√3	0.78	0.71	1.13	1.02	∞
Liquid permittivity - Temperature Uncertainty	2.5	R	√3	0.23	0.26	0.33	0.38	∞
Combined Standard Uncertainty		RSS				10.16	10.03	
Expanded Uncertainty (95% Confidence interval)		k				20.32	20.06	

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4. Measurement System

4.1 Specific Absorption Rate (SAR) Definition

SAR is related to the rate at which energy is absorbed per unit mass in an object exposed to a radio field. The SAR distribution in a biological body is complicated and is usually carried out by experimental techniques or numerical modeling. The standard recommends limits for two tiers of groups, occupational/controlled and general population/uncontrolled, based on a person's awareness and ability to exercise control over his or her exposure. In general, occupational/controlled exposure limits are higher than the limits for general population/uncontrolled.

The SAR definition is the time derivative (rate) of the incremental energy (dW) absorbed by (dissipated in) an incremental mass (dm) contained in a volume element (dv) of a given density (ρ). The equation description is as below:

$$\mathbf{SAR} = \frac{d}{dt}\left(\frac{dW}{dm}\right) = \frac{d}{dt}\left(\frac{dW}{\rho dv}\right)$$

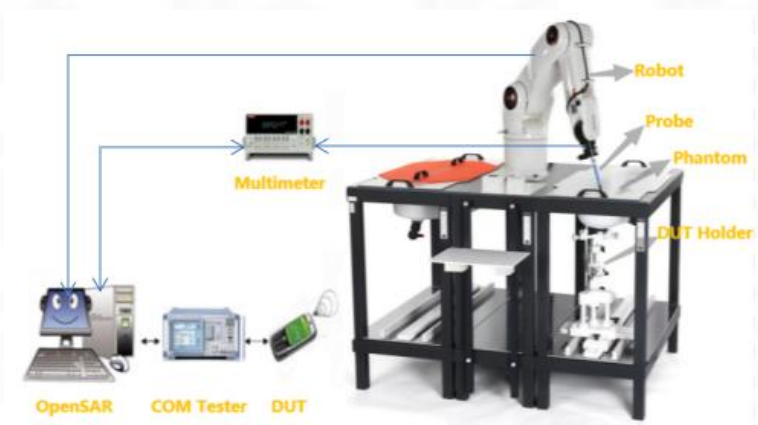
SAR is expressed in units of Watts per kilogram (W/kg) SAR measurement can be related to the electrical field in the tissue by

$$\mathbf{SAR} = \frac{\sigma E^2}{\rho}$$

Where: σ is the conductivity of the tissue,
ρ is the mass density of the tissue and E is the RMS electrical field strength.

4.2 MVG SAR System

4.2.1 SAR system diagram



4.2.2 Robot

A standard high precision 6-axis robot (Denso) with teaches pendant with Scanning System
· It must be able to scan all the volume of the phantom to evaluate the tridimensional distribution of SAR.
· Must be able to set the probe orthogonal of the surface of the phantom (±30°).
· Detects stresses on the probe and stop itself if necessary to keep the integrity of the probe.

4.2.3 E-Field Probe

For the measurements, the Specific Dosimetric SSE2 E-Field Probe with following specifications is used:

- Dynamic range: 0.01-100 W/kg
- Tip diameter: 2mm for SSE2
- Distance between probe tip and sensor centre: 1mm for SSE2
- Distance between sensor centre and the inner phantom surface: 2mm for f>=4GHz.
- Probe linearity: <0.25dB.
- Axial Isotropy: <0.25dB.
- Spherical Isotropy: <0.50dB.
- Calibration range: 150 to 6000 MHz for head & body simulating liquid
- Angle between probe axis (evaluation axis) and surface normal line: less than 20°.

4.2.4 Phantoms

SAM Phantom

For the measurements the Specific Anthropomorphic Mannequin (SAM) defined by the IEEE SCC-34/SC2 group is used. The probe scanning of the E-Field is done in the 2 halves of the normalized head. The normalized shape of the phantom corresponds to the dimensions of 90% of an adult head size. It enables the dosimetric evaluation of left and right-hand phone usage and includes an additional flat phantom part for the simplified body performance check.The phantom set-up includes a cover, which prevents the evaporation of the liquid.

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SAM Phantom

The thickness of the phantom amounts to 2 mm±0.2 mm. The materials for the phantom do not affect the radiation of the device under test (DUT) : εr' <5
The head is filled with tissue simulating liquid. The hand do not have to be modeled.

TWIN SAM phantom			
	Mechanical	Electrical	
Overall thickness	2±0.2 mm(except ear area)	Relative permittivity	3.4
Dimensions	1000 mm(L) x 500 mm(W) x 200 mm(H)	Loss tangent	0.02
Maximum volume	27 L		
Material	Fiberglass based		

ELLIPTICAL Phantom

The phantom is for Body performance check filled with tissue-equivalent liquid to a depth of at least 150 mm, whose shell material is resistant to damage or reaction with tissue-equivalent liquid chemicals.

ELLI Phantom

The shape of the phantom is an ellipse with length 600mm±5mm and width 400mm±5mm.
The phantom shell is made of low-loss and low-permittivity material, having loss tangent tanδ ≤ 0.05 and relative permittivity:
εr' ≤ 5 for f ≤ 3 GHz
3 ≤εr' ≤ 5 for f > 3 GHz
The thickness of the bottom-wall of the flat phantom is 2.0 mm with a tolerance of ± 0.2 mm.

Technical & mechanical characteristics	
Shell thickness	2 mm ± 0.2 mm
Filling volume	25 L
Dimensions	600 mm x 400 mm x 200mm
Permittivity	4.4
Loss tangent	0.017

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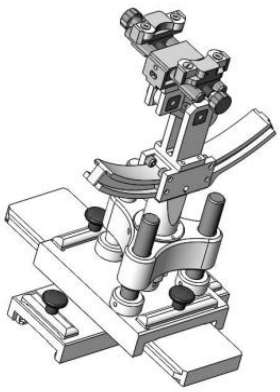
4.2.5 Device Holder



System Material	Permittivity	Loss tangent
Delrin	3.7	0.005

(The positioning system allows obtaining cheek and tilting position with a very good accuracy. In compliance with CENELEC, the tilt angle uncertainty is lower than 1°.)

System Material	Permittivity	Loss tangent
PMMA	2.9	0.028

4.2.6 Simulating Liquid

For SAR measurement of the field distribution inside the phantom, the phantom must be filled with homogeneous tissue simulating liquid to a depth of at least 15 cm. For head SAR testing, the liquid height from the ear reference point (ERP) of the phantom to the liquid top surface is larger than 15 cm. For body SAR testing, the liquid height from the center of the flat phantom to the liquid top surface is larger than 15 cm. The nominal dielectric values of the tissue simulating liquids in the phantom and the tolerance of 5%.

Head Liquid Depth	Body Liquid Depth

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The following table gives the recipes for tissue simulating liquid and the theoretical Conductivity/Permittivity.

Head (Reference IEEE1528)								
Frequency (MHz)	Water (%)	Sugar (%)	Cellulose (%)	Salt (%)	Preventol (%)	DGBE (%)	Conductivity σ (S/m)	Permittivity ε
750	41.1	57.0	0.2	1.4	0.2	0	0.89	41.9
835	40.3	57.9	0.2	1.4	0.2	0	0.90	41.5
900	40.3	57.9	0.2	1.4	0.2	0	0.97	41.5
1800, 1900, 2000	55.2	0	0	0.3	0	44.5	1.4	40.0
2450	55.0	0	0	0.1	0	44.9	1.80	39.2
2600	54.9	0	0	0.1	0	45.0	1.96	39.0
Frequency (MHz)	Water (%)	Hexyl Carbitol (%)			Triton X-100 (%)		Conductivity σ (S/m)	Permittivity ε
5200	62.52	17.24			17.24		4.66	36.0
5800	62.52	17.24			17.24		5.27	35.3
Body (From instrument manufacturer)								
Frequency (MHz)	Water (%)	Sugar (%)	Cellulose (%)	Salt (%)	Preventol (%)	DGBE (%)	Conductivity σ (S/m)	Permittivity ε
750	51.7	47.2	0	0.9	0.1	0	0.96	55.5
835	50.8	48.2	0	0.9	0.1	0	0.97	55.2
900	50.8	48.2	0	0.9	0.1	0	1.05	55.0
1800, 1900, 2000	70.2	0	0	0.4	0	29.4	1.52	53.3
2450	68.6	0	0	0.1	0	31.3	1.95	52.7
2600	68.2	0	0	0.1	0	31.7	2.16	52.5
Frequency(MHz)	Water	DGBE (%)			Salt (%)		Conductivity σ (S/m)	Permittivity ε
5200	78.60	21.40			/		5.30	49.00
5800	78.50	21.40			0.1		6.00	48.20

5. System Verification

5.1 Purpose of System Check

The system performance check verifies that the system operates within its specifications. System and operator errors can be detected and corrected. It is recommended that the system performance check be performed prior to any usage of the system in order to guarantee reproducible results. The system performance check uses normal SAR measurements in a simplified setup with a well characterized source. The setup was selected to give a high sensitivity to all parameters that might fail or vary over time. The system check does not intend to replace the calibration of the components, but indicates situations where the system uncertainty is exceeded due to drift or failure.

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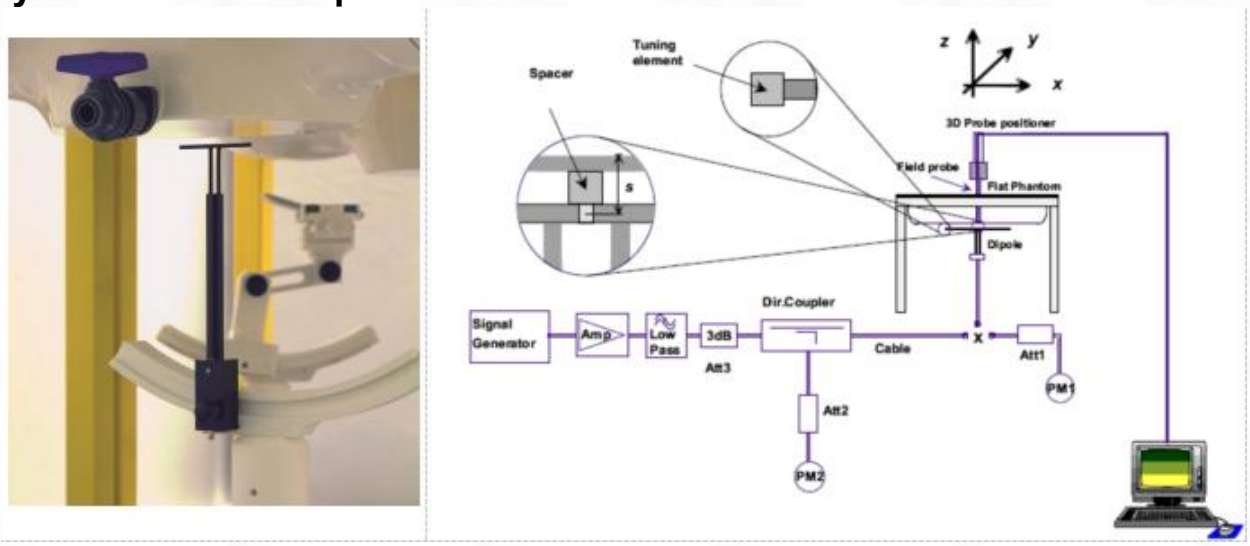
5.2 System Check Setup



6. TEST POSITION CONFIGURATIONS

According to KDB 648474 D04 Handset, handsets are tested for SAR compliance in head, body-worn accessory and other use configurations described in the following subsections.

6.1 Head Exposure Conditions

Head exposure is limited to next to the ear voice mode operations. Head SAR compliance is tested according to the test positions defined in IEEE Std 1528-2013 using the SAM phantom illustrated as below.

6.1.1 Two Imaginary Lines on the Handset

(a) The vertical center line passes through two points on the front side of the handset - the midpoint of the width w t of the handset at the level of the acoustic output, and the midpoint of the width w b of the bottom of the handset.

(b) The horizontal line is perpendicular to the vertical center line and passes through the center of the acoustic output. The horizontal line is also tangential to the face of the handset at point A.

(c) The two lines intersect at point A. Note that for many handsets, point A coincides with the center of the acoustic output; however, the acoustic output may be located elsewhere on the horizontal line. Also note that the vertical center line is not necessarily parallel to the front face of the handset, especially for clamshell handsets, handsets with flip covers, and other irregularly shaped handsets.

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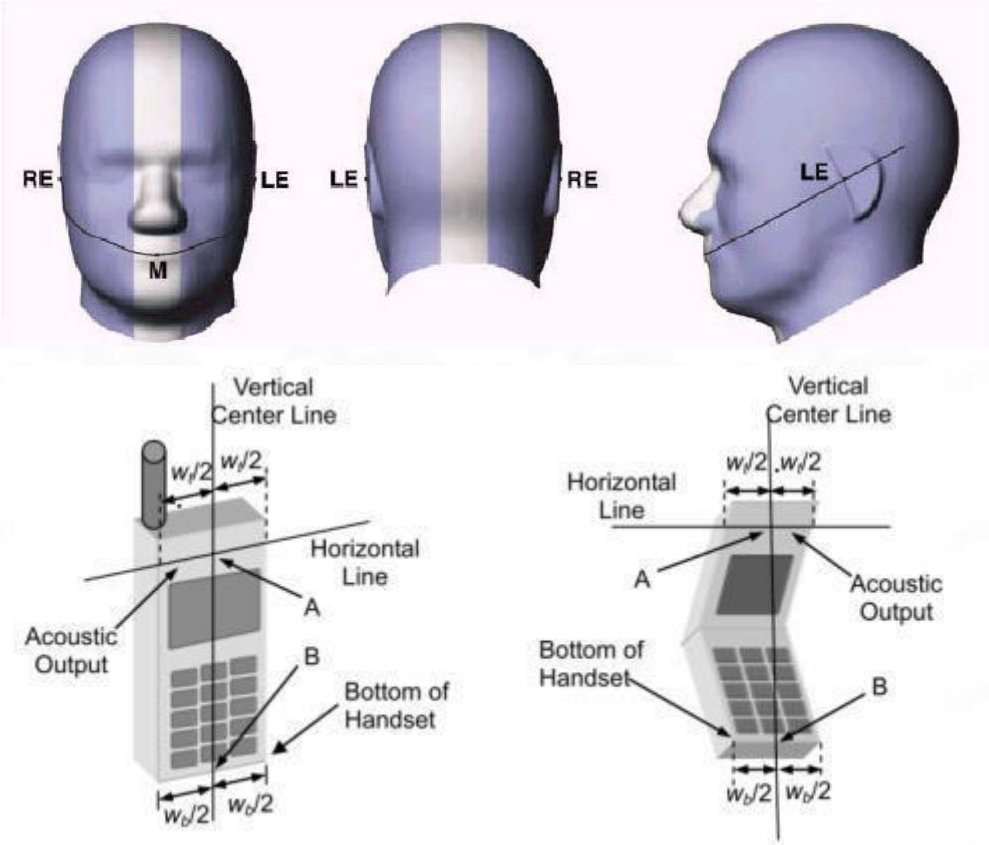


6.1.2 Two Imaginary Lines on the Handset

(a) To position the device with the vertical center line of the body of the device and the horizontal line crossing the center piece in a plane parallel to the sagittal plane of the phantom. While maintaining the device in this plane, align the vertical center line with the reference plane containing the three ear and mouth reference point (M: Mouth, RE: Right Ear, and LE: Left Ear) and align the center of the ear piece with the line RE-LE.

(b) To move the device towards the phantom with the ear piece aligned with the line LE-RE until the phone touched the ear. While maintaining the device in the reference plane and maintaining the phone contact with the ear, move the bottom of the phone until any point on the front side is in contact with the cheek of the phantom or until contact with the ear is lost.

6.1.3 Titled Position

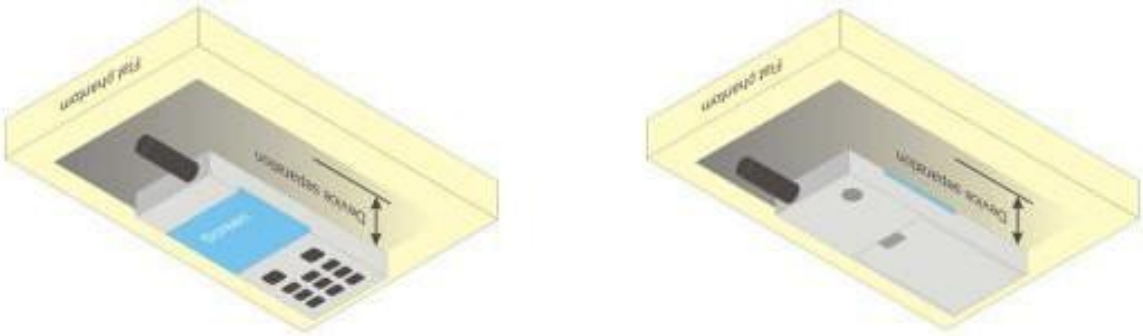
(a) To position the device in the “cheek” position described above.
(b) While maintaining the device the reference plane described above and pivoting against the ear, moves it outward away from the mouth by an angle of 15 degrees or until contact with the ear is lost.

6.2 Body-worn Position Conditions

Body-worn accessory exposure is typically related to voice mode operations when handsets are carried in body-worn accessories. The body-worn accessory procedures in KDB 447498 are used to test for body-worn accessory SAR compliance, without a headset connected to it. This enables the test results for such configuration to be compatible with that required for hotspot mode when the body-worn accessory test separation distance is greater than or equal to that required for hotspot mode. When the reported SAR for a body-worn accessory.

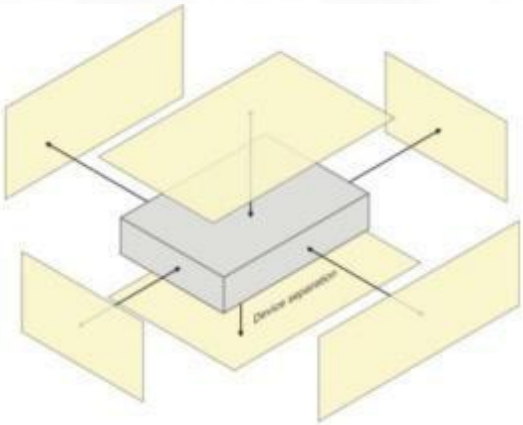
Body-worn accessories that do not contain metallic or conductive components may be tested according to worst-case exposure configurations, typically according to the smallest test separation distance required for the group of body-worn accessories with similar operating and exposure characteristics. All body-worn accessories containing metallic components are tested in conjunction with the host device.

Body-worn accessory SAR compliance is based on a single minimum test separation distance for all wireless and operating modes applicable to each body-worn accessory used by the host, and according to the relevant voice and/or data mode transmissions and operations. If a body-worn accessory supports voice only operations in its normal and expected use conditions, testing of data mode for body-worn compliance is not required. A conservative minimum test separation distance for supporting off-the-shelf body-worn accessories that may be acquired by users of consumer handsets is used to test for body-worn accessory SAR compliance. This distance is determined by the handset manufacturer, according to the requirements of Supplement C 01-01. Devices that are designed to operate on the body of users using lanyards and straps, or without requiring additional body-worn accessories, will be tested using a conservative minimum test separation distance <= 5 mm to support compliance.



6.3 Hotspot Mode Exposure Position Conditions

For handsets that support hotspot mode operations, with wireless router capabilities and various web browsing functions, the relevant hand and body exposure conditions are tested according to the hotspot SAR procedures in KDB 941225. A test separation distance of 10 mm is required between the phantom and all surfaces and edges with a transmitting antenna located within 25 mm from that surface or edge. When the form factor of a handset is smaller than 9 cm x 5 cm, a test separation distance of 5 mm (instead of 10 mm) is required for testing hotspot mode. When the separation distance required for body-worn accessory testing is larger than or equal to that tested for hotspot mode, in the same wireless mode and for the same surface of the phone, the hotspot mode SAR data may be used to support body-worn accessory SAR compliance for that particular configuration (surface).



6.4 Product Specific 10g Exposure Consideration

According with FCC KDB 648474 D04, for smart phones with a display diagonal dimension > 15.0 cm or an overall diagonal dimension > 16.0 cm that provide similar mobile web access and multimedia support found in mini-tablets or UMPC mini-tablets that support voice calls next to the ear, unless it is confirmed otherwise through KDB inquiries, the following phablet procedures should be applied to evaluate SAR compliance for each applicable wireless modes and frequency band. Devices marketed as phablets, regardless of form factors and operating characteristics must be tested as a phablet to determine SAR compliance;

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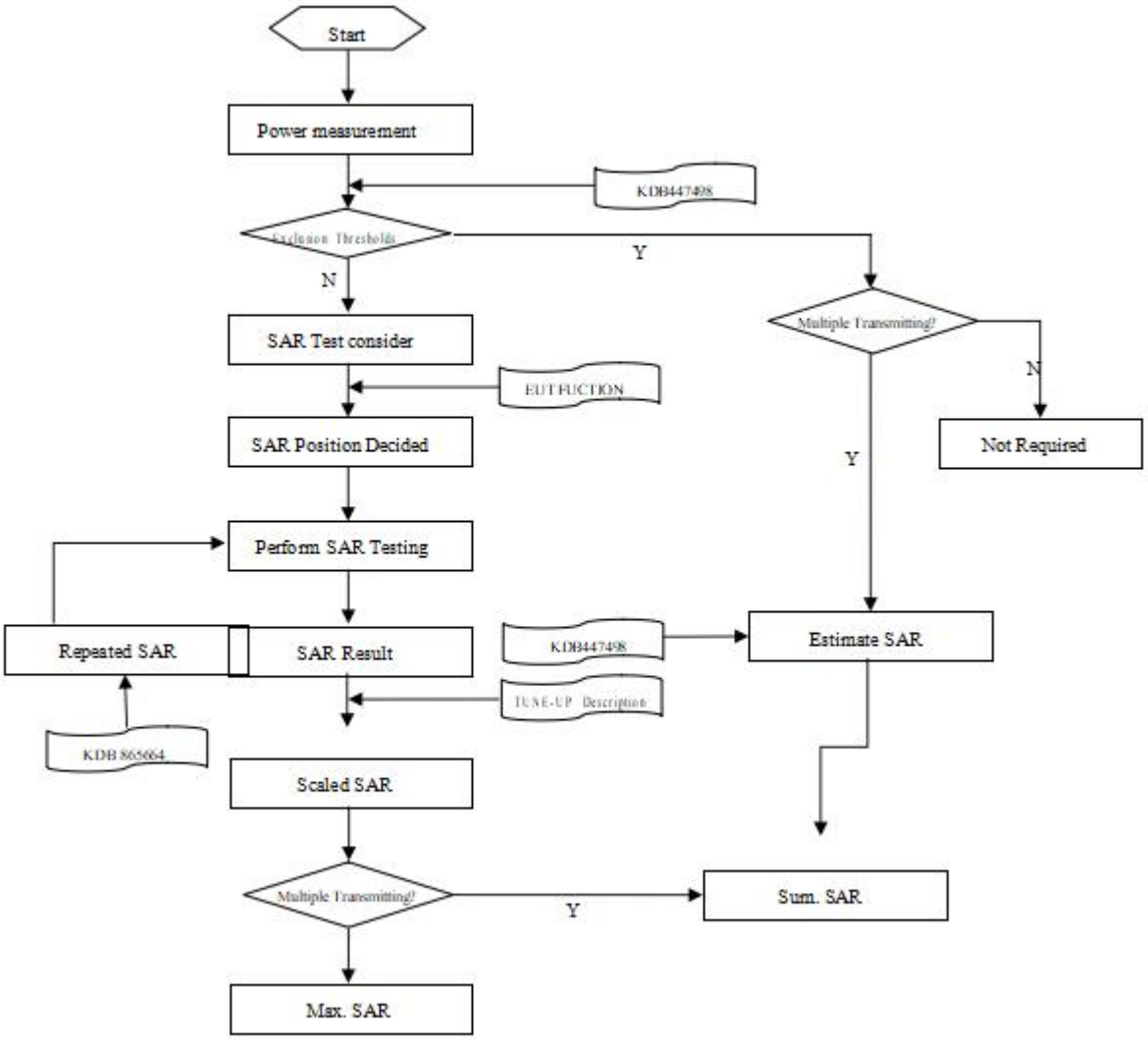
7. Measurement Procedure

7.1 Measurement Process Diagram

Body SAR



7.2 SAR Scan General Requirement

Probe boundary effect error compensation is required for measurements with the probe tip closer than half a probe tip diameter to the phantom surface. Both the probe tip diameter and sensor offset distance must satisfy measurement protocols; to ensure probe boundary effect errors are minimized and the higher fields closest to the phantom surface can be correctly measured and extrapolated to the phantom surface for computing 1 g SAR. Tolerances of the post-processing algorithms must be verified by the test laboratory for the scan resolutions used in the SAR measurements, according to the reference distribution functions specified in IEEE Std 1528-2013.

			≤3GHz	>3GHz
Maximum distance from closest measurement point (geometric center of probe sensors) to phantom surface			5±1 mm	½·δ·ln(2)±0.5 mm
Maximum probe angle from probe axis to phantom surface normal at the measurement location			30°±1°	20°±1°
Maximum area scan spatial resolution: Δx Area , Δy Area			≤ 2 GHz: ≤ 15 mm 2 – 3 GHz: ≤ 12 mm	3–4 GHz: ≤ 12 mm 4 – 6 GHz: ≤ 10 mm
			When the x or y dimension of the test device, in the measurement plane orientation, is smaller than the above, the measurement resolution must be ≤ the corresponding x or y dimension of the test device with at least one measurement point on the test device.	
Maximum zoom scan spatial resolution: Δx Zoom , Δy Zoom			≤ 2 GHz: ≤ 8 mm 2 –3 GHz: ≤ 5 mm*	3–4 GHz: ≤ 5 mm* 4 – 6 GHz: ≤ 4 mm*
Maximum zoom scan spatial resolution, normal to phantom surface	uniform grid: Δz Zoom (n)		≤ 5 mm	3–4 GHz: ≤ 4 mm
				4–5 GHz: ≤ 3 mm
				5–6 GHz: ≤ 2 mm
	graded grid	Δz Zoom (1): between 1st two points closest to phantom surface	≤ 4 mm	3–4 GHz: ≤ 3 mm
				4–5 GHz: ≤ 2.5 mm
				5–6 GHz: ≤ 2 mm
		Δz Zoom (n>1): between subsequent points	≤ 1.5·Δz Zoom (n-1)	
Minimum zoom scan volume	x, y, z		≥30 mm	3–4 GHz: ≥ 28 mm
				4–5 GHz: ≥ 25 mm
				5–6 GHz: ≥ 22 mm

Note:

1. δ is the penetration depth of a plane-wave at normal incidence to the tissue medium; see draft standard IEEE P1528- 2011 for details.
2. * When zoom scan is required and the reported SAR from the area scan based 1 g SAR estimation procedures of KDB 447498 is ≤ 1.4 W/kg, ≤ 8 mm, ≤ 7 mm and ≤ 5 mm zoom scan resolution may be applied, respectively, for 2 GHz to 3GHz, 3 GHz to 4 GHz and 4 GHz to 6 GHz.

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7.3 Measurement Procedure

The following steps are used for each test position

a. Establish a call with the maximum output power with a base station simulator. The connection between the mobile and the base station simulator is established via air interface

b. Measurement of the local E-field value at a fixed location. This value serves as a reference value for calculating a possible power drift.

c. Measurement of the SAR distribution with a grid of 8 to 16mm * 8 to16 mm and a constant distance to the inner surface of the phantom. Since the sensors cannot directly measure at the inner phantom surface, the values between the sensors and the inner phantom surface are extrapolated. With these values the area of the maximum SAR is calculated by an interpolation scheme.

d. Around this point, a cube of 30 * 30 * 30 mm or 32 * 32 *32 mm is assessed by measuring 5 or 8 * 5 or 8*4 or 5 mm. With these data, the peak spatial-average SAR value can be calculated.

7.4 Area & Zoom Scan Procedure

First Area Scan is used to locate the approximate location(s) of the local peak SAR value(s). The measurement grid within an Area Scan is defined by the grid extent, grid step size and grid offset. Next, in order to determine the EM field distribution in a three-dimensional spatial extension, Zoom Scan is required. The Zoom Scan is performed around the highest E-field value to determine the averaged SAR-distribution over 10 g. Area scan and zoom scan resolution setting follows KDB 865664 D01v01r04 quoted below.

When the 1 g SAR of the highest peak is within 2 dB of the SAR limit, additional zoom scans are required for other peaks within 2 dB of the highest peak that have not been included in any zoom scan to ensure there is no increase in SAR.

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8. Conducted RF Output Power

8.1 GSM

Mode: GSM850	Maximum Tune-up(dBm)	Burst Average Power (dBm)			Division Factors	Frame-Average Power (dBm)		
		CH128	CH190	CH251		CH128	CH190	CH251
		824.2MHz	836.6MHz	848.8MHz		824.2MHz	836.6MHz	848.8MHz
GSM	**31.50**	**31.31**	31.22	30.97	-9.03	22.28	22.19	21.94
Mode: GSM1900	**Maximum Tune-up(dBm)**	**Burst Average Power (dBm)**			**Division Factors**	**Frame-Average Power (dBm)**		
		CH512	CH661	CH810		CH512	CH661	CH810
		1850.2MHz	1880.0MHz	1909.8MHz		1850.2MHz	1880.0MHz	1909.8MHz
GSM	**27.50**	26.19	**27.18**	26.97	-9.03	17.16	18.15	17.94

Note:
1) Division Factors
To average the power, the division factor is as follows:
1Tx-slot = 1 transmit time slot out of 8 time slots=> conducted power divided by (8/1) => -9.03dB
2Tx-slots = 2 transmit time slots out of 8 time slots=> conducted power divided by (8/2) => -6.02dB
3Tx-slots = 3 transmit time slots out of 8 time slots=> conducted power divided by (8/3) => -4.26dB
4Tx-slots = 4 transmit time slots out of 8 time slots=> conducted power divided by (8/4) => -3.01dB

8.2 LTE

Band 2

LTE-FDD Band 2				Maximum Tune-up(dBm)	Conducted Power(dBm)		
Bandwidth	Modulation	RB allocation	RB offset		18607	18900	19193
					1850.7MHz	1880.0MHz	1909.3MHz
1.4MHz	QPSK	1	0	21.50	18.07	21.23	20.98
			2	21.50	18.20	21.28	20.99
			5	21.50	18.24	21.27	21.02
		3	0	21.50	18.32	21.31	20.96
			2	21.50	18.24	21.33	20.97
			3	21.50	18.21	21.40	20.89
		6	0	20.50	17.16	20.27	19.98
	16QAM	1	0	20.00	19.22	19.96	19.58
			2	20.00	19.29	19.97	19.56
			5	20.50	19.28	20.03	19.57
		3	0	20.50	19.10	20.25	19.98
			2	20.50	19.12	20.26	19.94
			3	20.50	19.12	20.35	19.91
		6	0	19.50	18.20	19.35	19.16

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Bandwidth	Modulation	RB allocation	RB offset	Maximum Tune-up(dBm)	18615	18900	19185
					1851.5MHz	1880.0MHz	1908.5MHz
3MHz	QPSK	1	0	20.50	19.18	20.34	20.01
			7	20.50	19.17	20.32	20.06
			14	20.50	19.25	20.31	20.11
		8	0	20.50	19.21	20.42	20.10
			4	20.50	19.19	20.41	20.09
			7	20.50	19.24	20.40	20.07
		15	0	20.50	19.22	20.39	20.06
	16QAM	1	0	20.50	19.20	20.38	20.05
			7	20.50	19.36	20.38	20.04
			14	20.50	19.35	20.37	20.02
		8	0	20.50	19.33	20.36	20.02
			4	20.50	19.32	20.36	20.01
			7	20.50	19.31	20.35	20.13
		15	0	20.50	19.30	20.34	18.15
Bandwidth	Modulation	RB allocation	RB offset	Maximum Tune-up(dBm)	18625	18900	19175
					1852.5MHz	1880.0MHz	1907.5MHz
5MHz	QPSK	1	0	19.50	18.20	19.23	15.85
			13	19.50	18.21	19.23	16.05
			24	19.50	18.28	19.24	15.08
		12	0	17.50	17.26	15.31	15.15
			6	17.50	17.28	15.41	15.15
			13	17.50	17.35	15.26	14.74
		25	0	17.50	17.27	15.32	14.97
	16QAM	1	0	17.00	16.51	15.10	15.12
			13	17.00	16.60	15.57	15.36
			24	17.00	16.61	15.04	14.39
		12	0	16.00	15.55	14.24	14.10
			6	16.00	15.84	14.38	14.11
			13	16.00	15.82	14.22	13.71
		25	0	16.00	15.76	14.29	13.89

LTE-FDD Band 2				Maximum Tune-up(dBm)	Conducted Power(dBm)		
Bandwidth	Modulation	RB allocation	RB offset		18650	18900	19150
					1855.0MHz	1880.0MHz	1905.0MHz
10MHz	QPSK	1	0	20.50	19.47	20.47	18.12
			25	20.50	19.39	20.44	18.20
			49	20.50	19.34	20.43	18.18
		25	0	20.50	19.43	20.42	18.17
			12	20.50	19.40	20.41	18.17
			25	20.50	19.38	20.40	18.16
		50	0	20.50	19.36	20.39	18.15
	16QAM	1	0	19.50	19.34	18.38	18.15
			25	19.50	19.40	18.38	18.14
			49	19.50	19.39	18.39	18.14
		25	0	19.50	19.37	18.39	18.13
			12	20.00	19.53	18.39	18.13
			25	20.00	19.55	18.39	15.38
		50	0	20.00	19.54	18.39	15.43

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Bandwidth	Modulation	RB allocation	RB offset	Maximum Tune-up(dBm)	18675	18900	19125
					1857.5MHz	1880.0MHz	1902.5MHz
15MHz	QPSK	1	0	16.50	15.54	16.31	14.66
			38	16.50	16.24	14.27	14.14
			74	17.00	16.57	14.11	13.09
		36	0	15.50	15.02	13.57	13.78
			18	15.50	15.23	13.48	13.31
			39	20.50	15.59	13.49	20.23
		75	0	20.50	15.31	13.54	20.22
	16QAM	1	0	21.50	15.14	13.90	21.10
			38	21.00	15.60	13.82	20.99
			74	21.00	16.11	13.65	20.66
		36	0	20.00	13.93	12.51	19.54
			18	19.50	14.16	12.43	19.38
			39	19.50	14.52	12.42	19.33
		75	0	20.00	14.22	12.47	19.52
Bandwidth	Modulation	RB allocation	RB offset	Maximum Tune-up(dBm)	18700	18900	19100
					1860.0MHz	1880.0MHz	1900.0MHz
20MHz	QPSK	1	0	**20.50**	19.57	**20.40**	18.25
			50	20.00	19.61	18.33	18.22
			99	20.00	19.57	18.33	18.24
		50	0	20.00	19.53	**18.32**	18.23
			25	20.00	19.62	18.32	18.22
			50	20.00	19.60	18.31	15.28
		100	0	20.00	19.64	18.31	15.33
	16QAM	1	0	20.00	19.62	18.31	15.35
			50	20.00	19.61	18.32	15.37
			99	20.00	19.60	18.31	15.38
		50	0	20.00	19.58	18.31	15.39
			25	20.00	19.57	18.30	15.40
			50	20.00	19.56	18.30	15.41
		100	0	20.00	19.68	18.30	15.41

Band 4

LTE-FDD Band 4				Maximum Tune-up(dBm)	Conducted Power(dBm)		
Bandwidth	Modulation	RB allocation	RB offset		19957	20175	20393
					1710.7MHz	1732.5MHz	1754.3MHz
1.4MHz	QPSK	1	0	21.50	21.09	20.51	20.24
			2	21.50	21.14	20.53	20.14
			5	21.50	21.11	20.56	20.12
		3	0	21.50	21.18	20.59	20.10
			2	21.50	21.13	20.64	20.13
			3	21.50	21.04	20.58	20.05
		6	0	20.50	20.13	19.53	19.06
	16QAM	1	0	20.00	19.67	19.86	18.85
			2	20.00	19.61	19.78	18.89
			5	20.00	19.63	19.81	18.92
		3	0	20.50	20.08	19.88	19.01
			2	20.50	20.11	19.84	19.03
			3	20.50	20.07	19.79	19.02
		6	0	19.50	19.29	18.85	18.36

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Bandwidth	Modulation	RB allocation	RB offset	Maximum Tune-up(dBm)	19965	20175	20385
					1711.5MHz	1732.5MHz	1753.5MHz
3MHz	QPSK	1	0	21.00	20.97	20.45	19.95
			7	21.50	21.01	20.44	19.99
			14	21.00	20.96	20.43	19.92
		8	0	20.50	20.01	19.47	19.20
			4	20.00	19.80	19.42	19.21
			7	20.50	20.16	19.39	19.13
		15	0	20.50	20.01	19.36	19.17
	16QAM	1	0	20.50	19.57	20.29	19.46
			7	20.50	19.48	20.29	19.42
			14	20.50	19.49	20.25	19.41
		8	0	19.50	19.37	18.75	18.50
			4	19.50	19.32	18.71	18.49
			7	19.50	19.38	18.68	18.52
		15	0	19.50	19.21	18.63	18.35
Bandwidth	Modulation	RB allocation	RB offset	Maximum Tune-up(dBm)	19975	20175	20375
					1712.5MHz	1732.5MHz	1752.5MHz
5MHz	QPSK	1	0	21.00	20.93	20.60	20.20
			13	21.00	20.84	20.58	20.19
			24	21.00	20.82	20.47	20.27
		12	0	20.50	20.07	19.44	19.13
			6	20.00	19.95	19.35	19.22
			13	20.50	20.08	19.51	19.23
		25	0	20.50	20.11	19.48	19.09
	16QAM	1	0	20.50	20.21	19.80	18.33
			13	20.50	20.08	19.67	18.34
			24	20.50	20.13	19.63	18.37
		12	0	19.50	19.18	18.59	18.33
			6	19.50	19.16	18.64	18.25
			13	19.50	19.14	18.57	18.26
		25	0	19.50	19.29	18.60	18.36

LTE-FDD Band 4				Maximum Tune-up(dBm)	Conducted Power(dBm)		
Bandwidth	Modulation	RB allocation	RB offset		20000	20175	20350
					1715.0MHz	1732.5MHz	1750.0MHz
10MHz	QPSK	1	0	21.50	21.01	20.68	20.11
			25	21.00	20.89	20.51	20.12
			49	21.00	20.83	20.36	20.13
		25	0	20.50	20.12	19.61	19.20
			12	20.00	19.89	19.49	19.15
			25	20.00	19.84	19.32	19.10
		50	0	20.00	19.94	19.42	19.08
	16QAM	1	0	20.00	19.98	19.84	19.52
			25	20.00	19.80	19.73	19.55
			49	20.00	19.66	19.55	19.56
		25	0	19.50	19.29	18.80	18.28
			12	19.50	19.27	18.72	18.35
			25	19.50	19.29	18.68	18.30
		50	0	19.50	19.14	18.74	18.38

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Bandwidth	Modulation	RB allocation	RB offset	Maximum Tune-up(dBm)	20025	20175	20325
					1717.5MHz	1732.5MHz	1747.5MHz
15MHz	QPSK	1	0	21.00	20.85	20.73	20.20
			38	21.00	20.71	20.53	20.17
			74	21.00	20.54	20.32	20.13
		36	0	20.50	20.02	19.51	19.27
			18	20.00	19.86	19.54	19.21
			38	20.00	19.89	19.37	19.09
		75	0	20.00	19.91	19.57	19.23
	16QAM	1	0	20.50	20.41	19.92	19.67
			38	20.50	20.31	19.67	19.58
			74	20.50	20.09	19.59	19.55
		36	0	19.50	19.14	18.82	18.57
			18	19.50	19.09	18.71	18.48
			38	19.50	19.03	18.65	18.49
		75	0	19.50	19.07	18.74	18.40
Bandwidth	Modulation	RB allocation	RB offset	Maximum Tune-up(dBm)	20050	20175	20300
					1720.0MHz	1732.5MHz	1745.0MHz
20MHz	QPSK	1	0	**21.50**	**21.03**	20.72	20.64
			50	21.00	20.88	20.47	20.51
			99	21.00	20.60	20.20	20.45
		50	0	20.50	**20.02**	19.73	19.20
			25	20.00	19.80	19.54	19.15
			50	20.00	19.79	19.37	19.24
		100	0	20.00	19.79	19.53	19.17
	16QAM	1	0	21.00	20.98	20.37	18.84
			50	21.00	20.62	19.99	18.71
			99	20.50	20.48	19.72	18.66
		50	0	19.50	19.18	18.95	18.50
			25	19.00	18.95	18.80	18.43
			50	19.00	18.84	18.59	18.46
		100	0	19.50	19.12	18.72	18.42

Band 5

LTE-FDD Band 5				Maximum Tune-up(dBm)	Conducted Power(dBm)		
Bandwidth	Modulation	RB allocation	RB offset		20407	20525	20643
					824.7MHz	836.5MHz	848.3MHz
1.4MHz	QPSK	1	0	22.00	21.72	21.50	21.56
			2	22.00	21.73	21.58	21.63
			5	22.00	21.68	21.57	21.63
		3	0	22.00	21.79	21.71	21.52
			2	22.00	21.84	21.65	21.49
			3	22.00	21.76	21.65	21.52
		6	0	21.00	20.80	20.59	20.46
	16QAM	1	0	21.50	21.08	20.61	19.98
			2	21.50	21.07	20.69	20.08
			5	21.50	21.11	20.67	20.06
		3	0	21.00	20.91	20.47	20.13
			2	21.00	20.87	20.50	20.30
			3	21.00	20.82	20.48	20.28
		6	0	20.50	20.00	19.61	19.57

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Bandwidth	Modulation	RB allocation	RB offset	Maximum Tune-up(dBm)	20415	20525	20635
					825.5MHz	836.5MHz	847.5MHz
3MHz	QPSK	1	0	22.00	21.93	21.51	21.43
			7	22.00	21.86	21.49	21.44
			14	22.00	21.87	21.51	21.41
		8	0	21.00	20.82	20.52	20.41
			4	21.00	20.70	20.54	20.40
			7	21.00	20.86	20.57	20.53
		15	0	21.00	20.76	20.68	20.48
	16QAM	1	0	21.50	20.39	21.22	20.61
			7	21.50	20.36	21.28	20.53
			14	21.50	20.34	21.22	20.57
		8	0	20.00	19.95	19.78	19.73
			4	20.00	19.98	19.72	19.73
			7	20.00	19.85	19.72	19.67
		15	0	20.00	19.88	19.69	19.52

LTE-FDD Band 5				Maximum Tune-up(dBm)	Conducted Power(dBm)		
Bandwidth	Modulation	RB allocation	RB offset		20425	20525	20625
					826.5MHz	836.5MHz	846.5MHz
5MHz	QPSK	1	0	22.00	21.67	21.59	21.45
			13	22.00	21.62	21.53	21.43
			24	22.00	21.69	21.51	21.43
		12	0	21.00	20.85	20.46	20.44
			6	21.00	20.93	20.67	20.48
			13	21.00	20.84	20.59	20.39
		25	0	21.00	20.77	20.53	20.47
	16QAM	1	0	21.00	20.86	20.63	19.64
			13	21.00	20.82	20.65	19.62
			24	21.00	20.78	20.64	19.75
		12	0	20.00	19.82	19.69	19.41
			6	20.00	19.72	19.66	19.46
			13	20.00	19.68	19.65	19.50
		25	0	20.00	19.74	19.60	19.54
Bandwidth	Modulation	RB allocation	RB offset	Maximum Tune-up(dBm)	20450	20525	20600
					829.0MHz	836.5MHz	844.0MHz
10MHz	QPSK	1	0	**22.00**	**21.82**	21.64	19.32
			25	22.00	21.75	21.57	19.46
			49	22.00	21.51	21.44	19.34
		25	0	21.00	20.79	20.63	18.41
			13	21.00	**20.80**	20.50	18.43
			25	21.00	20.72	20.40	18.39
		50	0	21.00	20.70	20.58	18.38
	16QAM	1	0	21.00	20.66	20.81	18.40
			25	21.00	20.54	20.71	18.52
			49	20.50	20.41	18.54	18.57
		25	0	20.00	19.89	16.85	16.07
			13	20.00	19.99	16.65	16.19
			25	20.00	19.88	16.57	16.24
		50	0	20.00	19.81	16.75	16.17

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Band 7

LTE-FDD Band 7				Maximum Tune-up(dBm)	Conducted Power(dBm)		
Bandwidth	Modulation	RB allocation	RB offset		20775	21100	21425
					2502.5MHz	2535.0MHz	2567.5MHz
5MHz	QPSK	1	0	17.00	16.51	16.50	13.91
			12	17.50	17.16	16.98	14.26
			24	17.00	16.91	14.50	13.65
		12	0	16.00	15.80	13.88	13.28
			6	16.50	16.04	14.03	13.37
			13	16.50	16.03	13.91	13.15
		25	0	16.00	15.92	13.91	13.22
	16QAM	1	0	16.00	15.56	13.44	13.10
			12	16.50	16.28	13.93	13.46
			24	16.50	16.01	13.45	12.86
		12	0	15.00	14.87	13.02	12.33
			6	15.50	15.13	13.16	12.43
			13	15.50	15.12	13.03	12.21
		25	0	15.00	14.96	13.06	12.33
Bandwidth	Modulation	RB allocation	RB offset	Maximum Tune-up(dBm)	20800	21100	21400
					2505.0MHz	2535.0MHz	2565.0MHz
10MHz	QPSK	1	0	14.50	14.11	13.94	13.67
			24	14.50	14.09	13.93	13.66
			49	14.50	14.07	13.93	13.66
		25	0	14.50	14.06	13.93	13.65
			12	14.50	14.05	14.08	13.65
			25	14.50	14.04	14.13	13.64
		50	0	14.50	14.03	14.14	13.64
	16QAM	1	0	14.50	14.13	14.14	13.64
			24	14.50	14.24	14.14	13.64
			49	14.50	14.23	14.13	13.64
		25	0	14.50	14.23	14.13	13.63
			12	14.50	14.22	14.13	13.63
			25	14.50	14.22	14.13	13.63
		50	0	14.50	14.22	14.13	13.63

LTE-FDD Band 7				Maximum Tune-up(dBm)	Conducted Power(dBm)		
Bandwidth	Modulation	RB allocation	RB offset		20825	21100	21375
					2507.5MHz	2535.0MHz	2562.5MHz
15MHz	QPSK	1	0	15.00	14.55	14.98	14.91
			38	15.50	15.24	14.85	14.31
			74	15.50	15.47	14.95	13.93
		38	0	14.50	14.26	14.09	13.91
			18	15.00	14.52	14.00	13.57
			37	15.00	14.82	14.12	13.36
		75	0	15.00	14.55	14.10	13.64
	16QAM	1	0	14.50	14.35	14.42	14.20
			38	15.50	15.03	14.28	13.59
			74	15.50	15.25	14.40	13.21
		38	0	13.50	13.20	13.17	13.01
			18	13.50	13.48	13.08	12.66
			37	14.00	13.78	13.20	12.45
		75	0	13.50	13.49	13.18	12.73

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Bandwidth	Modulation	RB allocation	RB offset	Maximum Tune-up(dBm)	20850	21100	21350
					2510.0MHz	2535.0MHz	2560.0MHz
20MHz	QPSK	1	0	15.50	14.27	15.40	15.32
			49	15.00	14.95	14.91	14.52
			99	**16.00**	15.47	**15.83**	14.64
		50	0	14.50	13.81	14.13	13.93
			25	14.50	14.20	14.11	13.64
			50	15.00	14.80	**14.47**	13.55
		100	0	14.50	14.42	14.28	13.74
	16QAM	1	0	15.00	14.17	14.66	14.54
			49	15.00	14.88	14.16	13.79
			99	15.50	15.36	15.11	13.88
		50	0	13.50	12.94	13.21	13.08
			25	13.50	13.35	13.19	12.78
			50	14.00	13.71	13.56	12.70
		100	0	13.50	13.37	13.37	12.90

Band 12

LTE-FDD Band 12				Maximum Tune-up(dBm)	Conducted Power(dBm)		
Bandwidth	Modulation	RB allocation	RB offset		23017	23095	23173
					699.7MHz	707.5MHz	715.3MHz
1.4MHz	QPSK	1	0	21.50	14.99	21.27	21.36
			2	21.50	15.29	21.42	21.35
			5	21.50	17.11	21.38	21.35
		3	0	21.50	17.21	21.46	21.37
			2	22.00	17.36	21.52	21.36
			3	21.50	17.34	21.35	21.36
		6	0	21.50	16.20	20.43	21.34
	16QAM	1	0	21.50	15.97	20.58	21.35
			2	21.50	16.28	20.42	21.37
			5	21.50	16.23	20.44	21.38
		3	0	21.50	16.22	20.39	21.37
			2	21.50	16.37	20.36	21.38
			3	21.50	16.35	20.35	21.36
		6	0	20.00	15.21	19.73	19.50
Bandwidth	Modulation	RB allocation	RB offset	Maximum Tune-up(dBm)	23025	23095	23165
					700.5MHz	707.5MHz	714.5MHz
3MHz	QPSK	1	0	21.50	21.36	19.40	19.57
			7	21.50	21.41	19.40	19.54
			14	21.50	21.36	19.42	19.38
		8	0	21.00	20.60	18.60	18.62
			4	21.00	20.56	18.60	15.90
			7	20.50	20.31	18.52	15.81
		15	0	21.00	20.52	18.59	15.93
	16QAM	1	0	21.00	20.76	18.33	16.07
			7	21.00	20.77	18.54	16.05
			14	21.00	20.78	18.53	15.67
		8	0	20.00	19.68	17.02	15.23
			4	20.00	19.65	17.07	15.16
			7	19.50	19.35	17.03	15.04
		15	0	20.00	19.61	17.01	15.15

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LTE-FDD Band 12				Maximum Tune-up(dBm)	Conducted Power(dBm)		
Bandwidth	Modulation	RB allocation	RB offset		23035	23095	23155
					701.5MHz	707.5MHz	713.5MHz
5MHz	QPSK	1	0	20.50	16.44	20.28	18.59
			13	20.50	16.39	20.34	18.56
			24	20.50	16.37	20.29	18.54
		12	0	20.50	16.35	20.33	18.53
			6	20.50	16.34	20.30	18.52
			13	20.50	16.34	20.28	18.51
		25	0	20.50	16.33	20.26	18.55
	16QAM	1	0	20.50	16.34	20.36	18.65
			13	20.50	16.48	20.34	18.64
			24	20.50	16.48	20.33	18.63
		12	0	20.00	16.48	19.95	18.63
			6	19.00	16.48	18.68	18.62
			13	19.00	16.47	18.68	18.62
		25	0	19.00	16.47	18.68	18.61
Bandwidth	Modulation	RB allocation	RB offset	Maximum Tune-up(dBm)	23060	23095	23130
					704.0MHz	707.5MHz	711.0MHz
10MHz	QPSK	1	0	17.00	16.55	17.00	15.32
			25	**17.50**	**17.26**	15.20	15.38
			49	17.50	17.10	15.48	15.18
		25	0	16.50	16.22	14.39	14.40
			13	16.50	16.40	14.33	16.35
			25	16.50	**16.44**	14.42	16.42
		50	0	16.50	16.35	14.42	16.45
	16QAM	1	0	16.50	16.28	14.25	16.44
			25	17.00	16.97	14.27	16.64
			49	17.00	16.84	14.51	16.28
		25	0	16.00	15.40	13.61	15.58
			13	16.00	15.55	13.52	15.61
			25	20.00	15.63	13.60	19.61
		50	0	19.50	15.48	13.52	19.38

Band 17

LTE-FDD Band 17				Maximum Tune-up(dBm)	Conducted Power(dBm)		
Bandwidth	Modulation	RB allocation	RB offset		23755	23790	23825
					706.5MHz	710.0MHz	713.5MHz
5MHz	QPSK	1	0	21.50	21.32	19.61	17.08
			13	21.50	21.30	19.25	17.36
			24	21.50	21.44	19.47	16.51
		12	0	21.00	20.52	18.50	16.31
			6	19.00	18.74	18.14	16.34
			13	19.00	18.67	18.56	15.98
		25	0	19.00	18.71	18.05	16.17
	16QAM	1	0	19.00	18.54	15.79	16.14
			13	19.00	18.53	16.24	16.46
			24	19.00	18.56	15.66	13.97
		12	0	17.50	17.04	15.29	13.54
			6	17.50	17.09	15.45	13.60
			13	17.00	16.85	15.33	13.25
		25	0	17.00	16.94	15.36	13.47

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Bandwidth	Modulation	RB allocation	RB offset	Maximum Tune-up(dBm)	23780	23790	23800
					709.0MHz	710.0MHz	711.0MHz
10MHz	QPSK	1	0	20.00	15.66	19.50	19.75
			24	19.50	15.49	19.31	17.30
			49	**21.50**	**21.39**	19.54	17.07
		25	0	20.50	20.39	18.58	16.32
			12	20.50	20.30	18.43	16.41
			25	21.00	**20.59**	18.82	16.39
		50	0	20.50	20.44	18.31	16.38
	16QAM	1	0	21.50	21.05	18.97	16.24
			24	21.00	20.99	18.58	16.44
			49	21.00	20.97	18.97	16.08
		25	0	20.00	19.50	17.33	15.60
			12	20.00	19.63	17.41	15.64
			25	20.00	19.54	17.47	15.66
		50	0	19.00	18.88	17.43	15.58

8.3 Bluetooth

	Mode	Maximum Tune-up(dBm)	Average Conducted Output Power (dBm)		
			0	39	78
			2402MHz	2441MHz	2480MHz
EDR	GFSK	1.00	0.77	0.77	-0.96
	π/4QPSK	2.50	1.86	2.24	-0.17
	8DPSK	**3.00**	2.17	**2.56**	0.10

Channel	Frequency (GHz)	Max. Tune-up Power (dBm)	Max. Power (mW)	Test distance (mm)	Exclusion thresholds for 1-g SAR(mW)	RF exposure evaluation required
39	2.441	3.00	2.00	0	10	No

Note

1. Per KDB 447498 D01 General RF Exposure Guidance v06, the 1-g SAR test exclusion thresholds for 300 MHz to 6 GHz at *test separation distances* ≤ 40 cm are determined by:

MHz	5	10	15	20	25	mm
150	39	77	116	155	194	*SAR Test Exclusion Threshold* (mW)
300	27	55	82	110	137	
450	22	45	67	89	112	
835	16	33	49	66	82	
900	16	32	47	63	79	
1500	12	24	37	49	61	
1900	11	22	33	44	54	
2450	10	19	29	38	48	
3600	8	16	24	32	40	
5200	7	13	20	26	33	
5400	6	13	19	26	32	
5800	6	12	19	25	31	

*When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine estimated SAR. .

2. The output power of all data rate were prescan, just the worst case (the lowest data rate) of all mode were shown in report.

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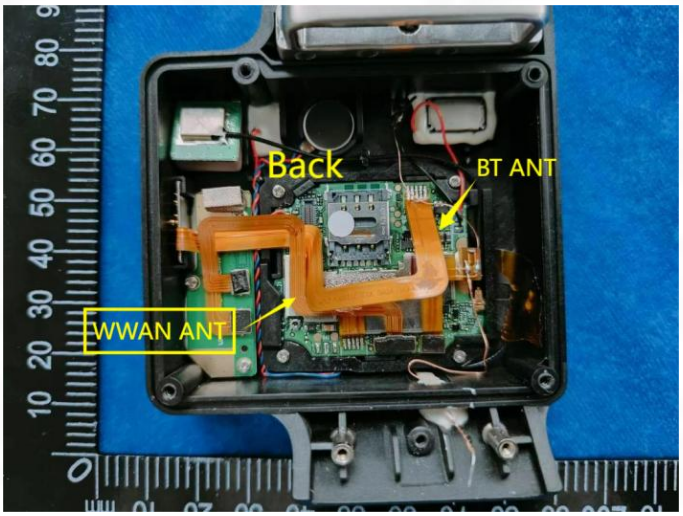
9. Test Exclusion Consideration

Antenna information:



WWAN Main Antenna	GSM/LTE TX/RX
BT Antenna	BT TX/RX
Note: 1. KDB 447498 D01v06, this device is used in ankle without voice communication, so we just need to consider ankle-worn condition with 10-g Extremity SAR.	

9.1 SAR Test Exclusion Consideration Table

Per KDB 447498 requires when the standalone SAR test exclusion of section 4.3.1 is applied to an antenna that transmits simultaneously with other antennas, the standalone SAR must be estimated according to the following format to determine simultaneous transmission SAR test exclusion:

(max.power of channel, including tune-up tolerance, mW) / (min. test separation distance, mm)] · [√f(GHz) / x] W/kg for test separation distances ≤ 50 mm;
where x = 7.5 for 1-g SAR, and x= 18.75 for 10-g SAR.
0.4 W/Kg for 1-g SAR and 1.0 W/kg for 10-g SAR, when the test separation distances is > 50 mm

Mode	Channel	Frequency (GHz)	Max tune-up power (dBm)	Max. Power (mW)	Exposure Position	Extremity
					Test Dist.(mm)	0
BT	39	2.441	3.00	2.00	Estimated 10g SAR(W/kg)	0.033

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10. Test Result

Extremity(0mm Gap)												
Mode	Position	Ch.	Freq. (MHz)	Power Drift (%)	10g Meas SAR (W/kg)	Duty cycle (%)	Duty cycle Factor	Meas. Power (dBm)	Max. tune-up power (dBm)	Scaling Factor	10g Reported SAR (W/kg)	Meas. No.
GSM 850	Back	128	824.2	-2.750	0.245	100.00	1.000	31.31	31.50	1.045	**0.256**	1#
Extremity(0mm Gap)												
Mode	Position	Ch.	Freq. (MHz)	Power Drift (%)	10g Meas SAR (W/kg)	Duty cycle (%)	Duty cycle Factor	Meas. Power (dBm)	Max. tune-up power (dBm)	Scaling Factor	10g Reported SAR (W/kg)	Meas. No.
GSM 850	Back	661	1880.0	-1.420	0.163	100.00	1.000	27.18	27.50	1.076	**0.175**	2#

Extremity(0mm Gap)													
Mode	Channel Type	Position	Ch.	Freq. (MHz)	Power Drift (%)	10g Meas SAR (W/kg)	Duty cycle (%)	Duty cycle Factor	Meas. Power (dBm)	Max. tune-up power (dBm)	Scaling Factor	10g Reported SAR (W/kg)	Meas. No.
Band 2 (BW: 20MHz)	1RB	Back	18900	1880.0	-1.550	0.121	100.00	1.000	20.40	20.50	1.023	**0.124**	3#
	50%RB	Back	18900	1880.0	-0.940	0.100	100.00	1.000	18.32	18.50	1.042	0.104	/
Extremity(0mm Gap)													
Mode	Channel Type	Position	Ch.	Freq. (MHz)	Power Drift (%)	10g Meas SAR (W/kg)	Duty cycle (%)	Duty cycle Factor	Meas. Power (dBm)	Max. tune-up power (dBm)	Scaling Factor	10g Reported SAR (W/kg)	Meas. No.
Band 4 (BW: 20MHz)	1RB	Back	20050	1720.0	-1.300	0.101	100.00	1.000	21.03	21.50	1.114	**0.113**	4#
	50%RB	Back	20050	1720.0	2.955	0.089	100.00	1.000	20.02	20.50	1.117	0.099	/
Extremity(0mm Gap)													
Mode	Channel Type	Position	Ch.	Freq. (MHz)	Power Drift (%)	10g Meas SAR (W/kg)	Duty cycle (%)	Duty cycle Factor	Meas. Power (dBm)	Max. tune-up power (dBm)	Scaling Factor	10g Reported SAR (W/kg)	Meas. No.
Band 5 (BW: 10MHz)	1RB	Back	20450	829.0	-3.010	0.127	100.00	1.000	21.82	22.00	1.042	**0.132**	5#
	50%RB	Back	20450	829.0	3.058	0.095	100.00	1.000	20.80	21.00	1.047	0.099	/
Extremity(0mm Gap)													
Mode	Channel Type	Position	Ch.	Freq. (MHz)	Power Drift (%)	10g Meas SAR (W/kg)	Duty cycle (%)	Duty cycle Factor	Meas. Power (dBm)	Max. tune-up power (dBm)	Scaling Factor	10g Reported SAR (W/kg)	Meas. No.
Band 7 (BW: 20MHz)	1RB	Back	21100	2535.0	2.050	0.169	100.00	1.000	15.83	16.00	1.040	**0.176**	6#
	50%RB	Back	21100	2535.0	1.365	0.153	100.00	1.000	14.47	14.50	1.007	0.154	/
Extremity(0mm Gap)													
Mode	Channel Type	Position	Ch.	Freq. (MHz)	Power Drift (%)	10g Meas SAR (W/kg)	Duty cycle (%)	Duty cycle Factor	Meas. Power (dBm)	Max. tune-up power (dBm)	Scaling Factor	10g Reported SAR (W/kg)	Meas. No.
Band 12 (BW: 10MHz)	1RB	Back	23060	704.0	-1.850	0.047	100.00	1.000	17.26	17.50	1.057	**0.050**	7#
	50%RB	Back	23060	704.0	-2.097	0.040	100.00	1.000	16.44	16.50	1.014	0.041	/
Extremity(0mm Gap)													
Mode	Channel Type	Position	Ch.	Freq. (MHz)	Power Drift (%)	10g Meas SAR (W/kg)	Duty cycle (%)	Duty cycle Factor	Meas. Power (dBm)	Max. tune-up power (dBm)	Scaling Factor	10g Reported SAR (W/kg)	Meas. No.
Band 17 (BW: 10MHz)	1RB	Back	23780	709.0	-1.370	0.040	100.00	1.000	21.39	21.50	1.026	**0.041**	8#
	50%RB	Back	23780	709.0	1.068	0.035	100.00	1.000	20.59	21.00	1.099	0.038	/

Note:

1. The maximum SAR Value of each test band is marked bold.
2. SAR plot is provided only for the highest measured SAR in each exposure configuration, wireless mode and frequency band combination.
3. Per KDB 447498 D01 v06, for each exposure position, if the highest output power channel Reported SAR ≤ 2.0 W/kg, other channels SAR testing is not necessary.
4. Per KDB 447498 D01 v06, ankle-worn use is evaluated with the device positioned at 0mm from a flat phantom filled with head tissue-equivalent medium.
5. Per KDB 447498 D01 v06, the report SAR is measured SAR value adjusted for maximum tune-up tolerance. Scaling Factor=10^[(tune-up limit power(dBm) - Ave.power power (dBm))/10], where tune-up limit is the maximum rated power among all production units.
   Reported SAR(W/kg)=Measured SAR (W/kg)*Scaling Factor.

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11. SAR Measurement Variability

According to KDB 865664 D01, SAR measurement variability was assessed for each frequency band, which is determined by the SAR probe calibration point and tissue-equivalent medium used for the device measurements. When both head and body tissue-equivalent media are required for SAR measurements in a frequency band, the variability measurement procedures should be applied to the tissue medium with the highest measured SAR, using the highest measured SAR configuration for that tissue-equivalent medium. Alternatively, if the highest measured SAR for both head and body tissue-equivalent media are ≤ 1.45 W/kg and the ratio of these highest SAR values, i.e., largest divided by smallest value, is ≤ 1.10, the highest SAR configuration for either head or body tissue-equivalent medium may be used to perform the repeated measurement. These additional measurements are repeated after the completion of all measurements requiring the same head or body tissue-equivalent medium in a frequency band. The test device should be returned to ambient conditions (normal room temperature) with the battery fully charged before it is re-mounted on the device holder for the repeated measurement(s) to minimize any unexpected variations in the repeated results.

SAR repeated measurement procedure:

1. When the highest measured SAR is < 0.80 W/kg, repeated measurement is not required.
2. When the highest measured SAR is >= 0.80 W/kg, repeat that measurement once.
3. If the ratio of largest to smallest SAR for the original and first repeated measurements is > 1.20, or when the original or repeated measurement is >= 1.45 W/kg, perform a second repeated measurement.
4. If the ratio of largest to smallest SAR for the original, first and second repeated measurements is > 1.20, and the original, first or second repeated measurement is >= 1.5 W/kg, perform a third repeated measurement.

Note: For 10g SAR with factor 2.5, the highest measured 10g SAR is 0.245 < 2.0 W/kg, repeated measurement is not required.

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12. Simultaneous Transmission

Simultaneous transmission SAR test exclusion is determined for each operating configuration and exposure condition according to the reported standalone SAR of each applicable simultaneous transmitting antenna. When the sum of SAR 1g or 10g of all simultaneously transmitting antennas in an operating mode and exposure condition combination is within the SAR limit (SAR 1g 1.6 W/kg or SAR 10g 4.0 W/kg), the simultaneous transmission SAR is not required.
When the sum of SAR 1g is greater than the SAR limit (SAR 1g 1.6 W/kg or SAR 10g 4.0 W/kg), SAR test exclusion is determined by the SAR to Peak Location Ratio (SPLSR).

12.1 Simultaneous Transmission Mode Considerations

Simultaneous transmission SAR test exclusion is determined for each operating configuration and exposure condition according to the reported standalone SAR of each applicable simultaneous transmitting antenna. The device has 2 Tx antennas(WWAN antenna supporting GSM/LTE and BT antenna supporting BT). The 2 antennas can always transmit simultaneously. The work mode combination is showed as below table.

Application Simultaneous Transmission information:

NO.	Configuration	Extremity
1	WWAN+BT	Yes

12.2 Sum SAR of Simultaneous Transmission

Extremity

Band	Test Position	Reported SAR 10g (W/kg)		Σ SAR (W/kg) WWAN + BT	SPLSR	Remark
		WWAN	Bluetooth			
GSM 850	Back	0.256	0.033	**0.289**	N/A	N/A
GSM 1900	Back	0.175	0.033	0.208	N/A	N/A

Band	Test Position	RB allocation	Reported SAR 10g (W/kg)		Σ SAR (W/kg) WWAN + BT	SPLSR	Remark
			WWAN	Bluetooth			
Band 2 (BW: 20MHz)	Back	1RB	0.124	0.033	0.157	N/A	N/A
	Back	50%RB	0.104	0.033	0.137	N/A	N/A
Band 4 (BW: 20MHz)	Back	1RB	0.113	0.033	0.146	N/A	N/A
	Back	50%RB	0.099	0.033	0.132	N/A	N/A
Band 5 (BW: 10MHz)	Back	1RB	0.132	0.033	0.165	N/A	N/A
	Back	50%RB	0.099	0.033	0.132	N/A	N/A
Band 7 (BW: 20MHz)	Back	1RB	0.176	0.033	0.209	N/A	N/A
	Back	50%RB	0.154	0.033	0.187	N/A	N/A
Band 12 (BW: 10MHz)	Back	1RB	0.050	0.033	0.083	N/A	N/A
	Back	50%RB	0.041	0.033	0.074	N/A	N/A
Band 17 (BW: 10MHz)	Back	1RB	0.041	0.033	0.074	N/A	N/A
	Back	50%RB	0.038	0.033	0.071	N/A	N/A

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13. Test Equipment List

Description	Manufacturer	Model	Serial No./Version	Cal. Date	Cal. Due
E-Field Probe	MVG	SSE2	04/22 EPGO365	2023/02/06	2024/02/05
6 1/2 Digital Multimeter	Keithley	DMM6500	4527164	2022/11/24	2023/11/23
Wideband Radio Communication Tester	ROHDE & SCHWARZ	CMW500	161997	2022/11/24	2023/11/23
MXG Vector Signal Generator	Agilent	N5182A	MY46240163	2022/11/24	2023/11/23
E-Series Avg. Power Sensor	KEYSIGHT	E9300A	MY55050017	2023/03/24	2024/03/23
EPM Series Power Meter	KEYSIGHT	E4418B	MY41293435	2023/03/24	2024/03/23
10dB Attenuator	MIDWEST MICROWAVE	263-10dB	/	2023/03/24	2024/03/23
Coupler	MERRIMAC	CWM-10R-10.8G	LOT-83391	2023/03/24	2024/03/23
750MHz Validation Dipole	MVG	SID750	07/22 DIP 0G835-655	2023/02/06	2024/02/05
835MHz Validation Dipole	MVG	SID835	07/22 DIP 0G835-656	2023/02/06	2024/02/05
1800MHz Validation Dipole	MVG	SID1800	07/22 DIP 1G800-657	2023/02/06	2024/02/05
1900MHz Validation Dipole	MVG	SID1900	07/22 DIP 1G900-658	2023/02/06	2024/02/05
2600MHz Validation Dipole	MVG	SID2600	07/22 DIP 2G600-663	2023/02/06	2024/02/05
LIMESAR Dielectric Probe	MVG	SCLMP	06/22 OCPG88	/	/
ENA Series Network Analyzer	Agilent	E5071B	MY42301221	2022/11/24	2023/11/23
Thermometer	Riters	DT-232	21A11	2023/03/24	2024/03/23
Antenna network emulator	MVG	ANTA 74	07/22 ANTA 74	/	/
SAM Phantom	MVG	SAM	07/22 SAM149	/	/
Mobile Phone Positioning System	MVG	MSH 118	07/22 MSH 118	/	/
Mechanical Calibration Kit	PNA	/	/	/	/
Open SAR test software	MVG	/	V5.3.5	/	/

Note: For dipole antennas, BTF has adopted 3 years as calibration intervals, and on annual basis, every measurement dipole has been evaluated and is in compliance with the following criteria:

1. There is no physical damage on the dipole;
2. System validation with specific dipole is within 10% of calibrated value;
3. Return-loss in within 20% of calibrated measurement.
4. Impedance (real or imaginary parts) in within 5 Ohms of calibrated measurement.

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ANNEX A Simulating Liquid Verification Result

The dielectric parameters of the liquids were verified prior to the SAR evaluation using an SCLMP Dielectric Probe Kit.

Dielectric performance of tissue simulating liquid									
Frequency (MHz)	εr		σ(s/m)		Delta (εr)	Delta (σ)	Limit	Temp (℃)	Date
	Target	Measured	Target	Measured					
750	41.90	43.61	0.89	0.86	4.08%	-3.37%	±10%	20.0	25/9/2023
835	41.50	43.25	0.90	0.87	4.22%	-3.33%	±10%	20.0	25/9/2023
1800	40.00	41.53	1.40	1.37	3.83%	-2.14%	±10%	20.0	25/9/2023
1900	40.00	41.50	1.40	1.41	3.75%	0.71%	±10%	20.0	25/9/2023
2600	39.00	38.88	1.96	1.97	-0.31%	0.51%	±10%	20.0	25/9/2023
NOTE: The dielectric parameters of the tissue-equivalent liquid should be measured under similar ambient conditions and within 2 ℃ of the conditions expected during the SAR evaluation to satisfy protocol requirements.									

ANNEX B System Check Result

Comparing to the original SAR value provided by MVG, the validation data should be within its specification of 10 %(for 10 g).

Frequency (MHz)	Input Power (mW)	1g SAR (W/Kg)	10g SAR (W/Kg)	1g SAR 1W input power normalized (W/Kg)	10g SAR 1W input power normalized (W/Kg)	1g SAR Standard target (1W) (W/Kg)	10g SAR Standard target (1W) (W/Kg)	1g SAR Deviation	10g SAR Deviation
750	16	0.138	0.092	8.63	5.75	8.25	5.38	4.55%	6.88%
835	16	0.163	0.106	10.19	6.63	9.79	6.17	4.06%	7.37%
1800	16	0.588	0.312	36.75	19.50	39.33	20.61	-6.56%	-5.39%
1900	16	0.630	0.322	39.38	20.13	40.97	20.7	-3.89%	-2.78%
2600	16	0.866	0.421	54.13	26.31	57.14	24.48	-5.28%	7.49%

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System Performance Check Data (750 MHz)

System check at 750 MHz

Date of measurement: 25/9/2023

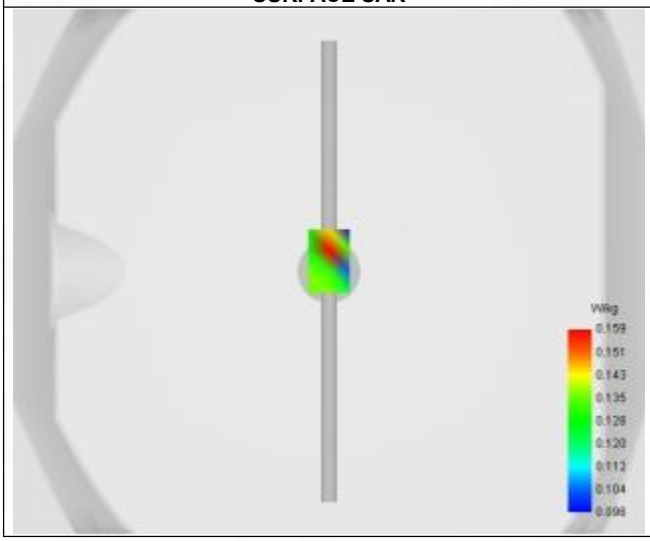
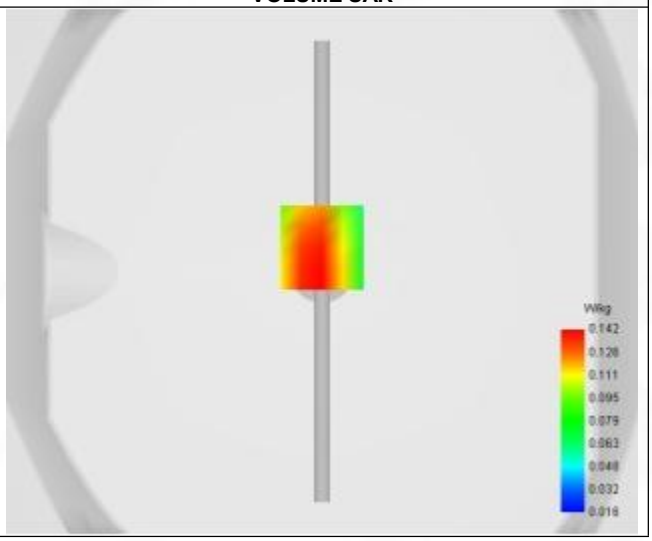
A. Experimental conditions.

Probe	SN 04/22 EPGO365
ConvF	1.65
Area Scan	dx=8mm dy=8mm, Adaptative 1 max
Zoom Scan	5x5x7,dx=8mm dy=8mm dz=5mm,Complete
Phantom	Validation plane
Device Position	Dipole
Band	CW750
Channels	Middle
Signal	CW

B. Permitivity

Frequency (MHz)	750.000
Relative permitivity (real part)	43.610
Relative permitivity (imaginary part)	21.460
Conductivity (S/m)	0.860

C. SAR Surface and Volume

SURFACE SAR	VOLUME SAR
	

Maximum location: X=0.00, Y=9.00 ; SAR Peak: 0.20 W/kg

D. SAR 1g & 10g

SAR 10g (W/Kg)	0.092
SAR 1g (W/Kg)	0.138
Variation (%)	-2.190
Horizontal validation criteria: minimum distance (mm)	0.000000
Vertical validation criteria: SAR ratio M2/M1 (%)	0.000000

E. Z Axis Scan

Z (mm)	0.00	4.00	9.00	14.00	19.00
SAR (W/Kg)	0.287	0.142	0.092	0.073	0.042

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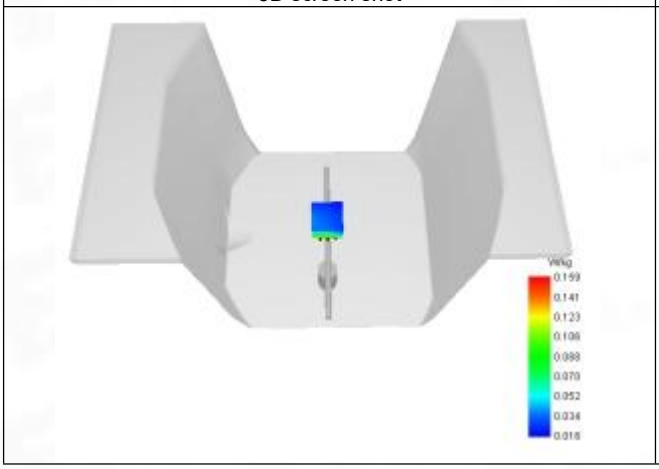
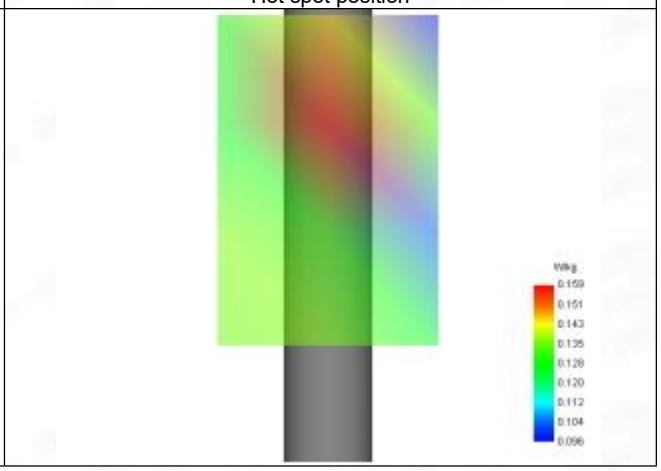
F. 3D Image

3D screen shot	Hot spot position
	

System Performance Check Data (835 MHz)

System check at 835 MHz

Date of measurement: 25/9/2023

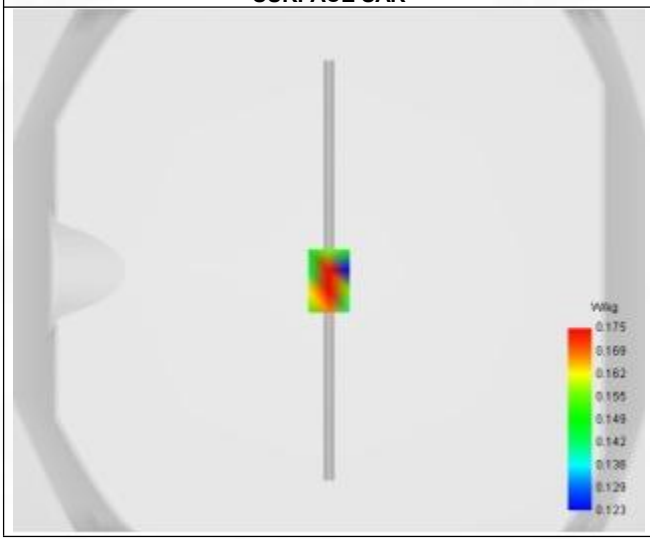
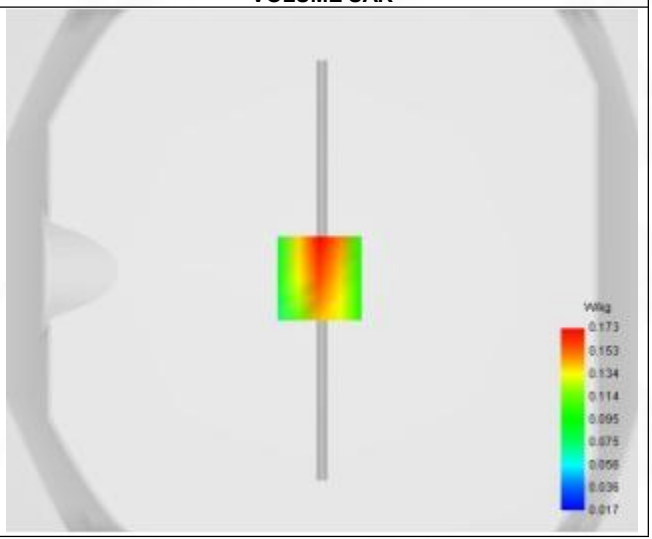
A. Experimental conditions.

Probe	SN 04/22 EPGO365
ConvF	1.68
Area Scan	dx=8mm dy=8mm, Adaptative 1 max
Zoom Scan	5x5x7,dx=8mm dy=8mm dz=5mm,Complete
Phantom	Validation plane
Device Position	Dipole
Band	CW835
Channels	Middle
Signal	CW

B. Permitivity

Frequency (MHz)	835.000
Relative permitivity (real part)	43.250
Relative permitivity (imaginary part)	19.490
Conductivity (S/m)	0.870

C. SAR Surface and Volume

SURFACE SAR	VOLUME SAR
	

Maximum location: X=-1.00, Y=-3.00 ; SAR Peak: 0.26 W/kg

D. SAR 1g & 10g

SAR 10g (W/Kg)	0.106
SAR 1g (W/Kg)	0.163
Variation (%)	-3.390
Horizontal validation criteria: minimum distance (mm)	0.000000
Vertical validation criteria: SAR ratio M2/M1 (%)	0.000000

E. Z Axis Scan

Z (mm)	0.00	4.00	9.00	14.00	19.00
SAR (W/Kg)	0.059	0.173	0.115	0.061	0.072

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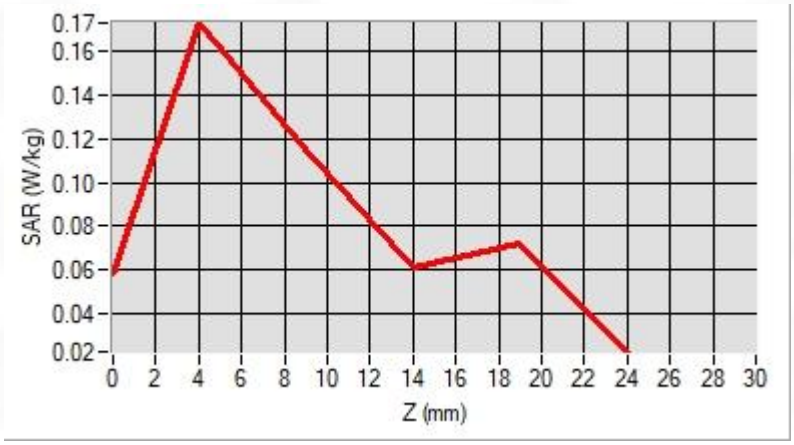
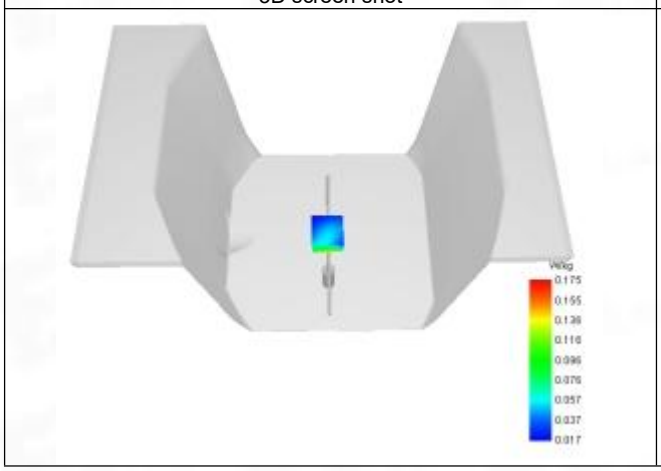
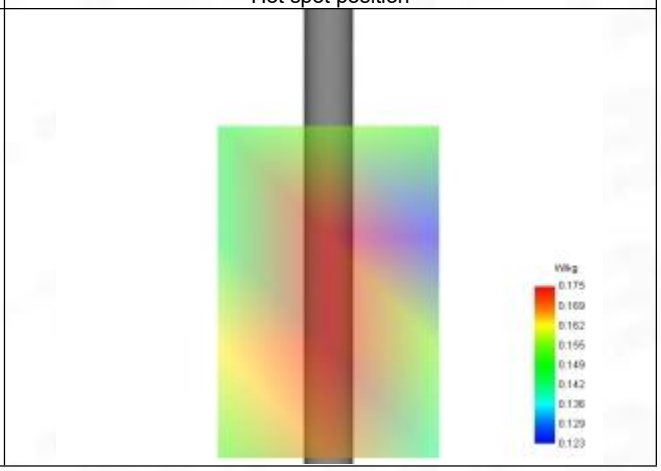


F. 3D Image

3D screen shot	Hot spot position
	

System Performance Check Data (1800 MHz)

System check at 1800 MHz

Date of measurement: 25/9/2023

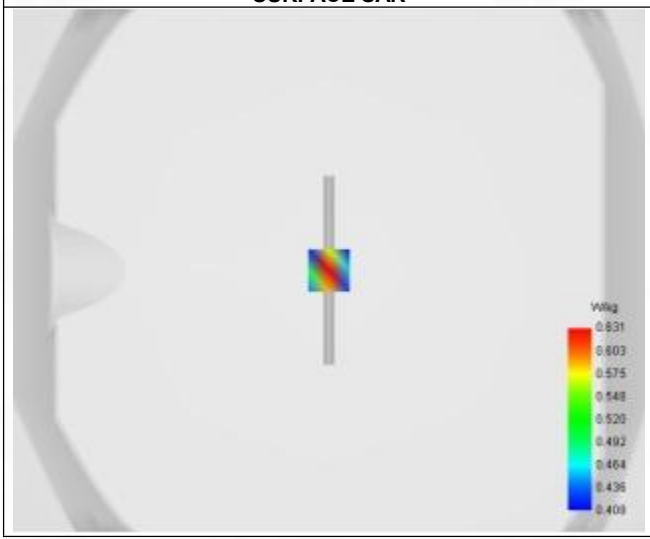
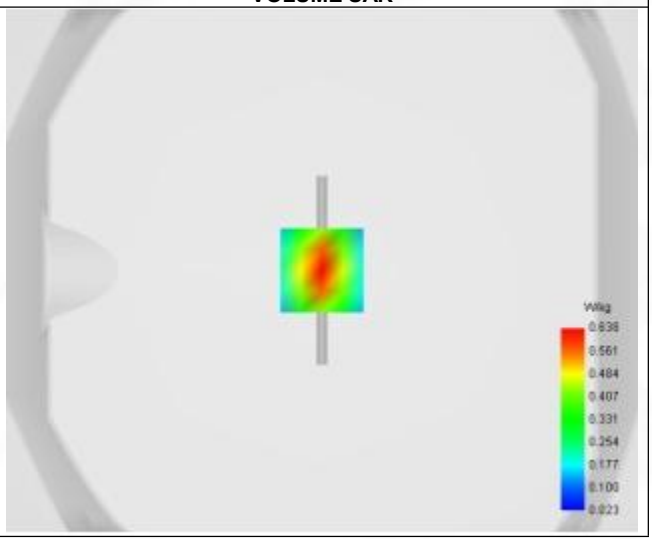
A. Experimental conditions.

Probe	SN 04/22 EPGO365
ConvF	1.96
Area Scan	dx=8mm dy=8mm, Adaptative 1 max
Zoom Scan	5x5x7,dx=8mm dy=8mm dz=5mm,Complete
Phantom	Validation plane
Device Position	Dipole
Band	CW1800
Channels	Middle
Signal	CW

B. Permitivity

Frequency (MHz)	1800.000
Relative permitivity (real part)	41.530
Relative permitivity (imaginary part)	14.090
Conductivity (S/m)	1.370

C. SAR Surface and Volume

SURFACE SAR	VOLUME SAR
	

Maximum location: X=0.00, Y=0.00 ; SAR Peak: 1.00 W/kg

D. SAR 1g & 10g

SAR 10g (W/Kg)	0.312
SAR 1g (W/Kg)	0.588
Variation (%)	-0.250
Horizontal validation criteria: minimum distance (mm)	0.000000
Vertical validation criteria: SAR ratio M2/M1 (%)	0.000000

E. Z Axis Scan

Z (mm)	0.00	4.00	9.00	14.00	19.00
SAR (W/Kg)	1.003	0.638	0.356	0.204	0.127

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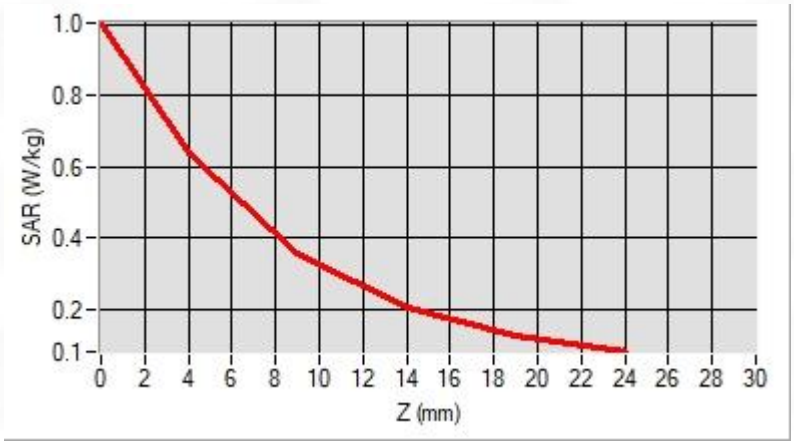
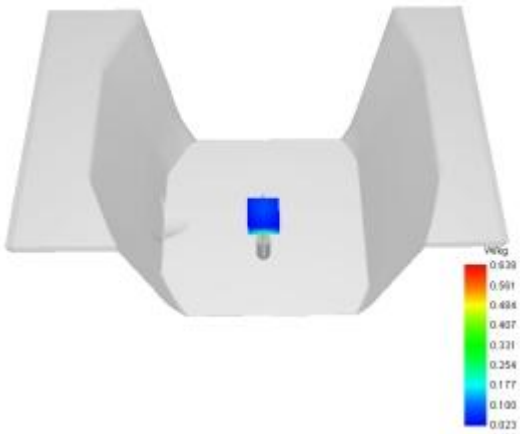
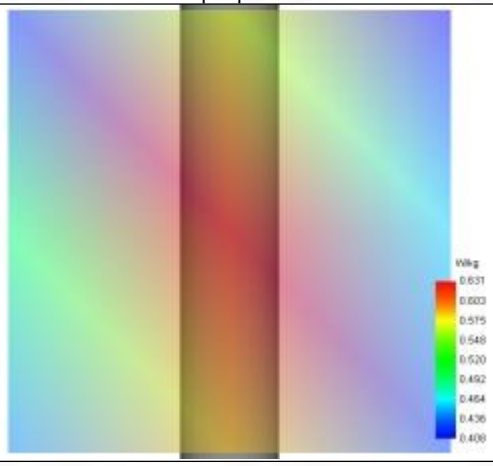


F. 3D Image

3D screen shot	Hot spot position
	

System Performance Check Data (1900 MHz)

System check at 1900 MHz

Date of measurement: 25/9/2023

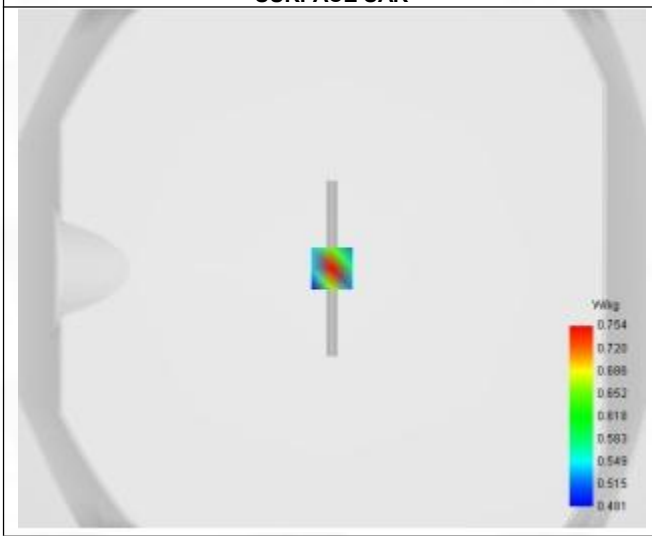
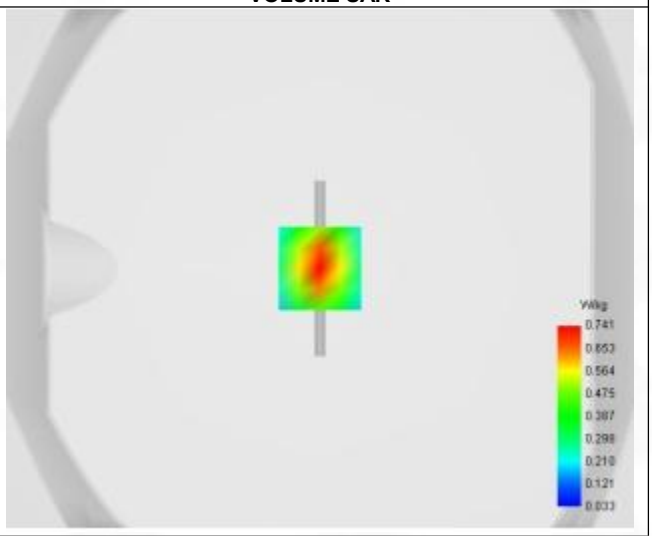
A. Experimental conditions.

Probe	SN 04/22 EPGO365
ConvF	2.24
Area Scan	dx=8mm dy=8mm, Adaptative 1 max
Zoom Scan	5x5x7,dx=8mm dy=8mm dz=5mm,Complete
Phantom	Validation plane
Device Position	Dipole
Band	CW1900
Channels	Middle
Signal	CW

B. Permitivity

Frequency (MHz)	1900.000
Relative permitivity (real part)	41.500
Relative permitivity (imaginary part)	13.380
Conductivity (S/m)	1.410

C. SAR Surface and Volume

SURFACE SAR	VOLUME SAR
	

Maximum location: X=0.00, Y=0.00 ; SAR Peak: 1.18 W/kg

D. SAR 1g & 10g

SAR 10g (W/Kg)	0.322
SAR 1g (W/Kg)	0.630
Variation (%)	-2.080
Horizontal validation criteria: minimum distance (mm)	0.000000
Vertical validation criteria: SAR ratio M2/M1 (%)	0.000000

E. Z Axis Scan

Z (mm)	0.00	4.00	9.00	14.00	19.00
SAR (W/Kg)	1.201	0.759	0.402	0.239	0.156

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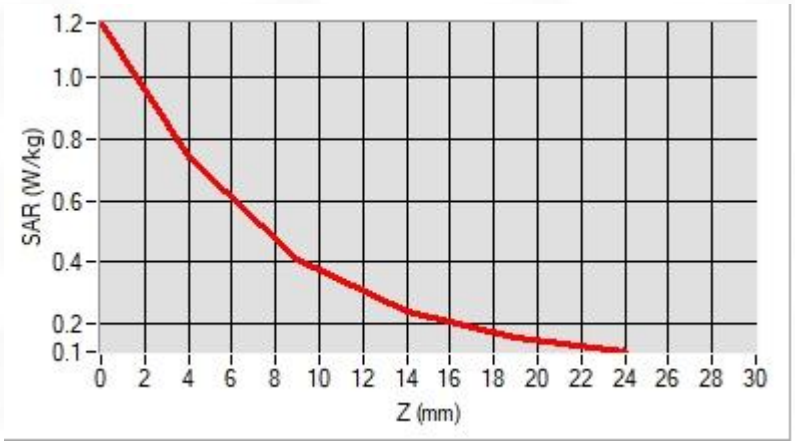
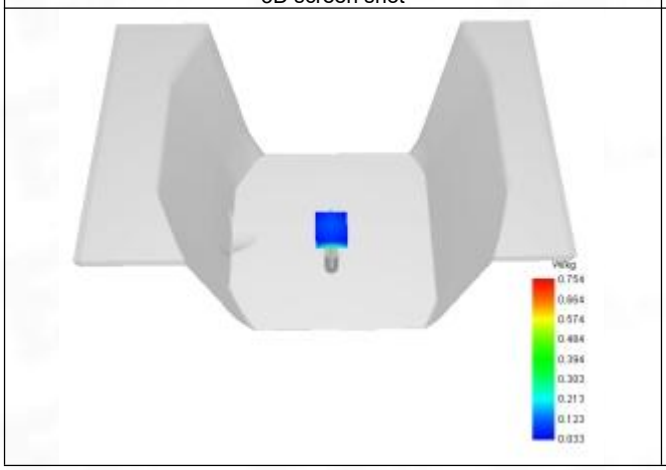
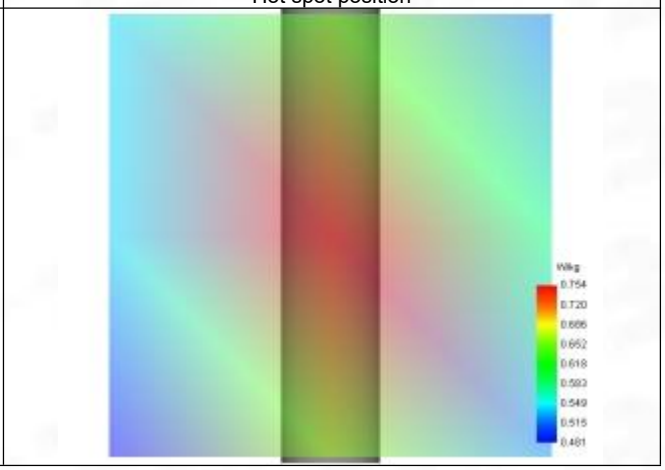


F. 3D Image

3D screen shot	Hot spot position
	

System Performance Check Data (2600 MHz)

System check at 2600 MHz

Date of measurement: 25/9/2023

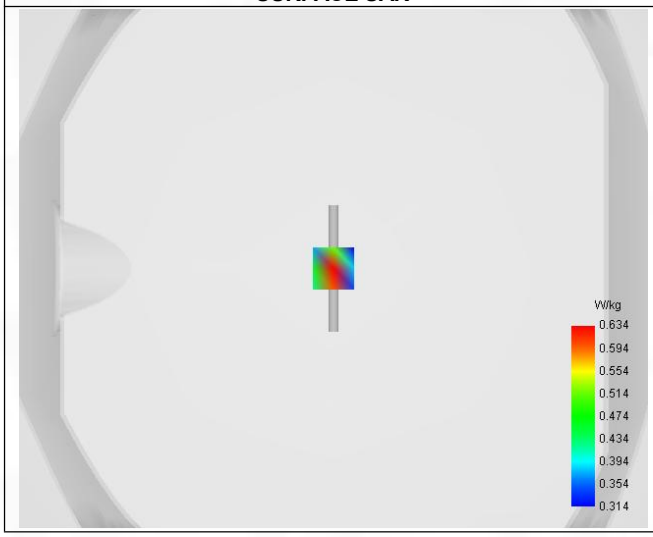
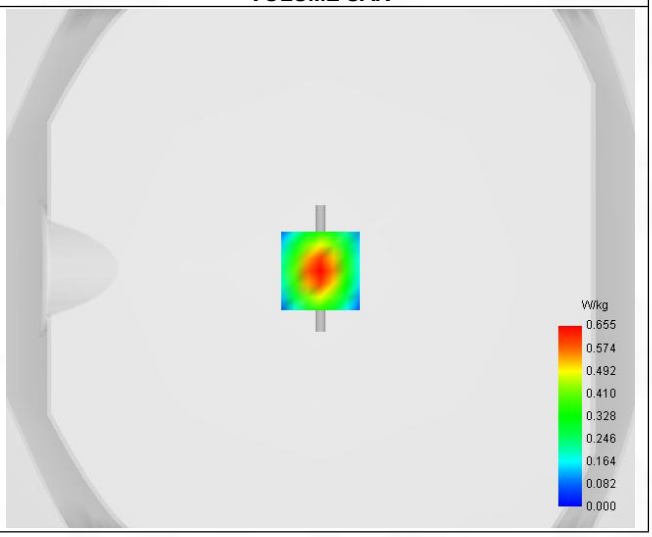
A. Experimental conditions.

Probe	SN 04/22 EPGO365
ConvF	2.40
Area Scan	dx=8mm dy=8mm, Adaptative 1 max
Zoom Scan	5x5x7,dx=8mm dy=8mm dz=5mm,Complete
Phantom	Validation plane
Device Position	Dipole
Band	CW2600
Channels	Middle
Signal	CW

B. Permitivity

Frequency (MHz)	2600.000
Relative permitivity (real part)	38.880
Relative permitivity (imaginary part)	12.690
Conductivity (S/m)	1.970

C. SAR Surface and Volume

SURFACE SAR	VOLUME SAR
	

Maximum location: X=0.00, Y=-1.00 ; SAR Peak: 1.02 W/kg

D. SAR 1g & 10g

SAR 10g (W/Kg)	0.421
SAR 1g (W/Kg)	0.866
Variation (%)	2.980
Horizontal validation criteria: minimum distance (mm)	0.000000
Vertical validation criteria: SAR ratio M2/M1 (%)	0.000000

E. Z Axis Scan

Z (mm)	0.00	4.00	9.00	14.00	19.00
SAR (W/Kg)	1.020	0.655	0.359	0.187	0.091

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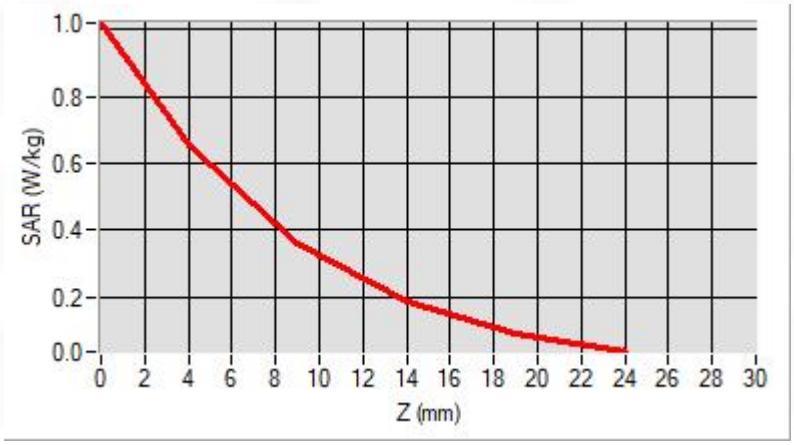
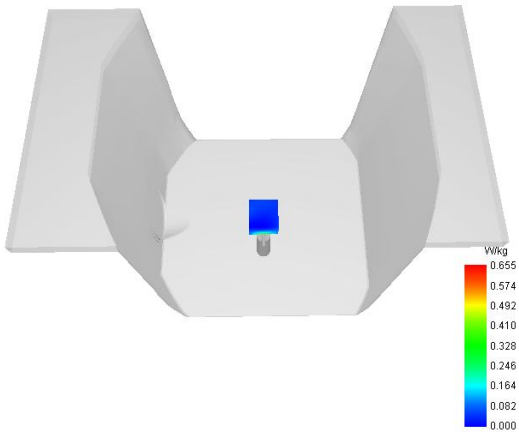
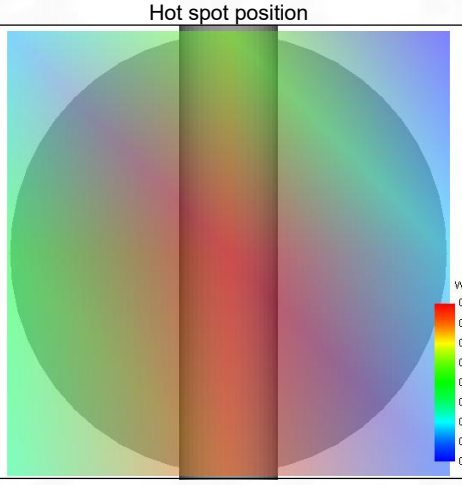


F. 3D Image

3D screen shot	Hot spot position
	

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ANNEX C Test Data

1-Extremity with back position in dist. 0mm Channel 128 in GSM 850

SAR Measurement at GSM850 (Body, Validation Plane)

Date of measurement: 25/9/2023

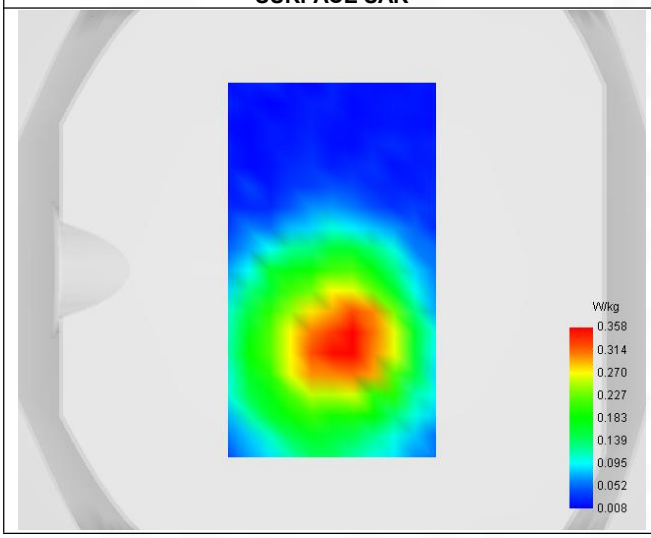
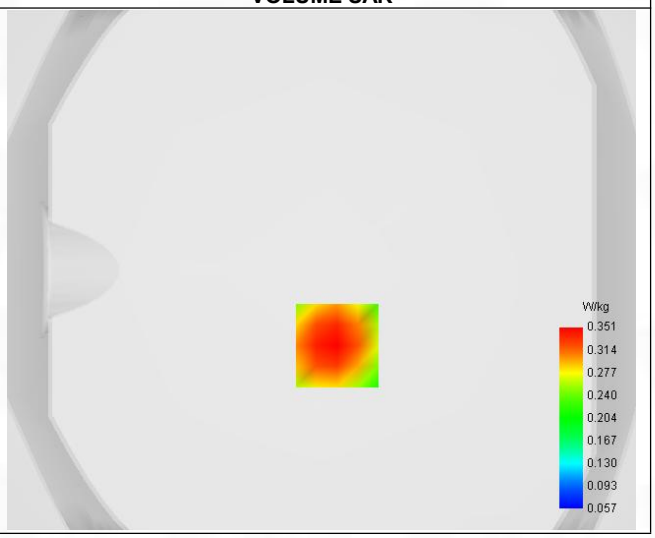
A. Experimental conditions.

Probe	SN 04/22 EPGO365
ConvF	1.68
Area Scan	surf_sam_plan.txt
Zoom Scan	5x5x7,dx=8mm dy=8mm dz=5mm,Complete
Phantom	Validation plane
Device Position	Body
Band	GSM850
Channels	Lower (128)
Signal	TDMA (GSM)
Modulation	GMSK

B. Permitivity

Frequency (MHz)	824.200
Relative permitivity (real part)	43.296
Relative permitivity (imaginary part)	19.740
Conductivity (S/m)	0.869

C. SAR Surface and Volume

SURFACE SAR	VOLUME SAR
	

Maximum location: X=6.00, Y=-29.00 ; SAR Peak: 0.46 W/kg

D. SAR 1g & 10g

SAR 10g (W/Kg)	0.245
SAR 1g (W/Kg)	0.359
Variation (%)	-2.750
Horizontal validation criteria: minimum distance (mm)	0.000000
Vertical validation criteria: SAR ratio M2/M1 (%)	0.000000

E. Z Axis Scan

Z (mm)	0.00	4.00	9.00	14.00	19.00
SAR (W/Kg)	0.459	0.351	0.251	0.182	0.136

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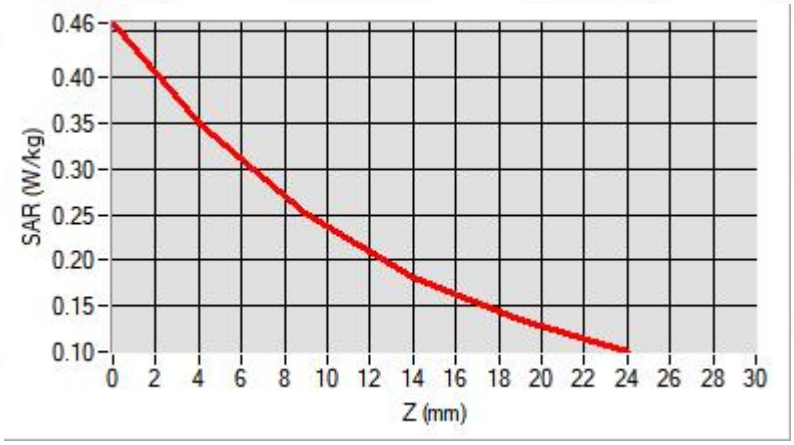
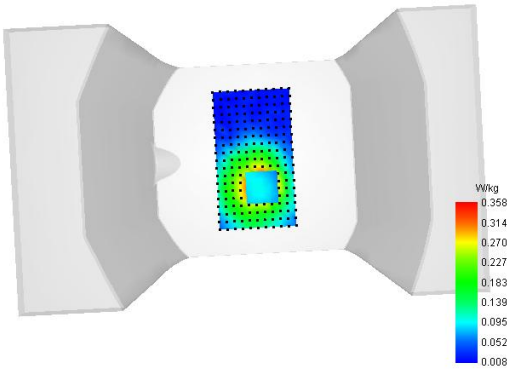
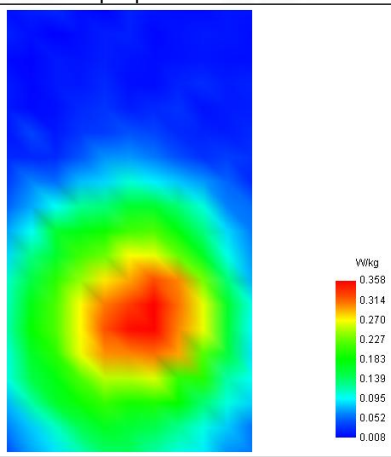


F. 3D Image

3D screen shot	Hot spot position
	

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2-Extremity with back position in dist. 0mm Channel 661 in GSM1900

SAR Measurement at GSM1900 (Body, Validation Plane)

Date of measurement: 25/9/2023

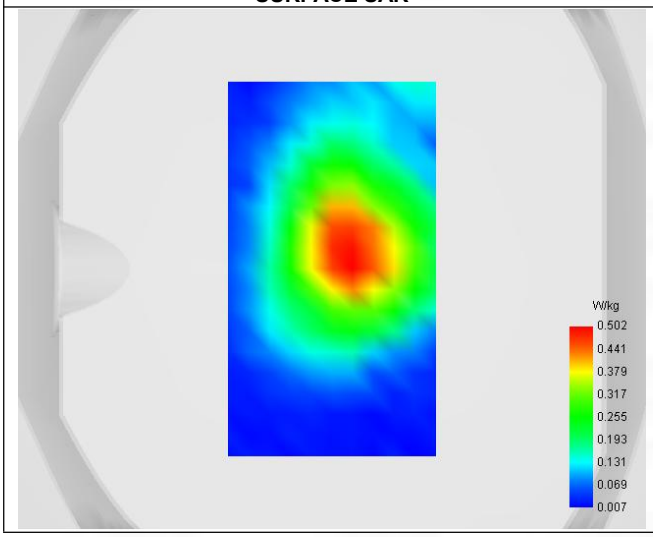
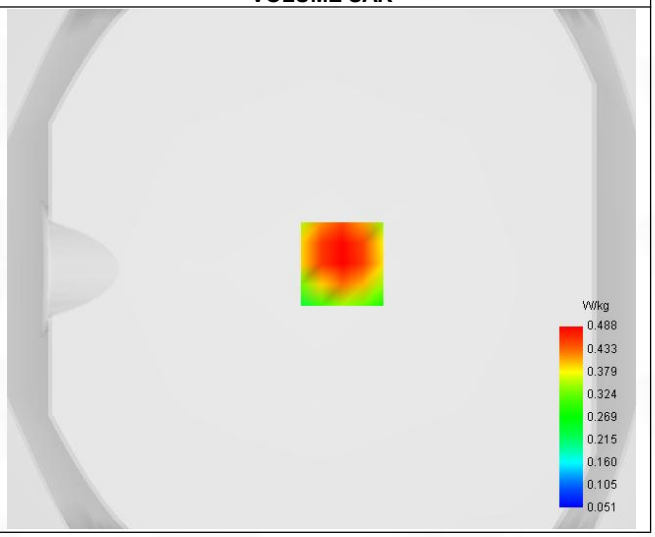
A. Experimental conditions.

Probe	SN 04/22 EPGO365
ConvF	1.96
Area Scan	surf_sam_plan.txt
Zoom Scan	5x5x7,dx=8mm dy=8mm dz=5mm,Complete
Phantom	Validation plane
Device Position	Body
Band	GSM1900
Channels	Middle (661)
Signal	TDMA (GSM)
Modulation	GMSK

B. Permitivity

Frequency (MHz)	1880.000
Relative permitivity (real part)	41.506
Relative permitivity (imaginary part)	13.522
Conductivity (S/m)	1.402

C. SAR Surface and Volume

SURFACE SAR	VOLUME SAR
	

Maximum location: X=8.00, Y=2.00 ; SAR Peak: 0.68 W/kg

D. SAR 1g & 10g

SAR 10g (W/Kg)	0.163
SAR 1g (W/Kg)	0.312
Variation (%)	-1.420
Horizontal validation criteria: minimum distance (mm)	0.000000
Vertical validation criteria: SAR ratio M2/M1 (%)	0.000000

E. Z Axis Scan

Z (mm)	0.00	4.00	9.00	14.00	19.00
SAR (W/Kg)	0.679	0.488	0.318	0.208	0.136

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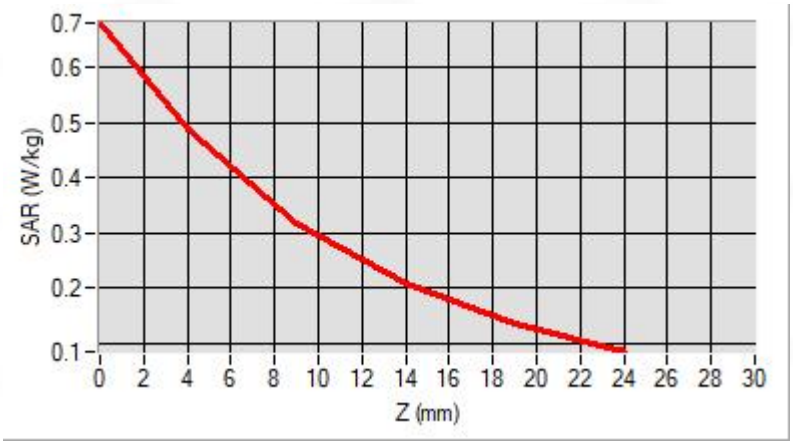
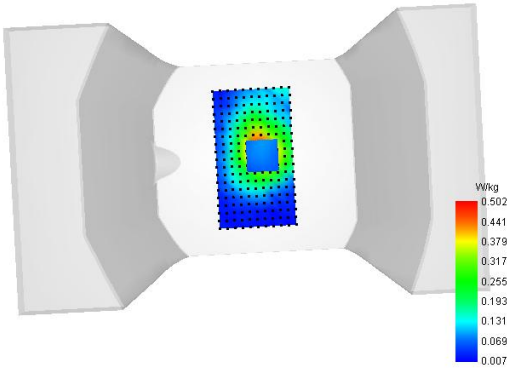
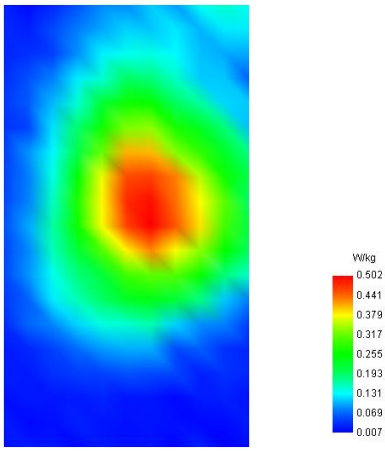


F. 3D Image

3D screen shot	Hot spot position
	

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3-Extremity with back position in dist. 0mm Channel 18900 in LTE band 2

SAR Measurement at LTE band 2 (Body, Validation Plane)

Date of measurement: 25/9/2023

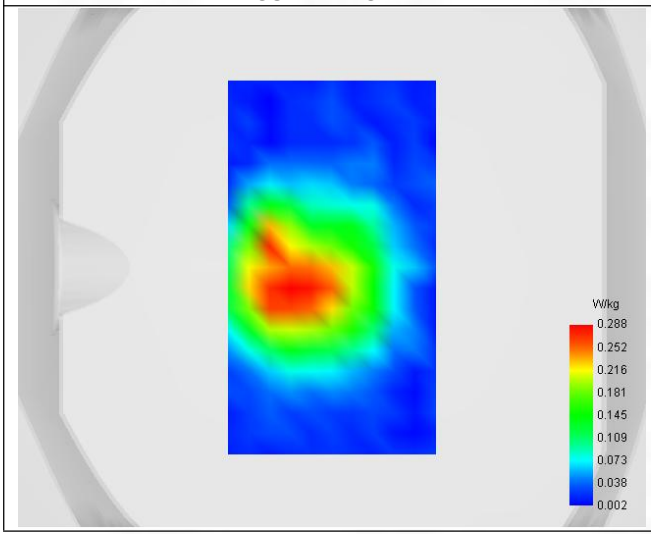
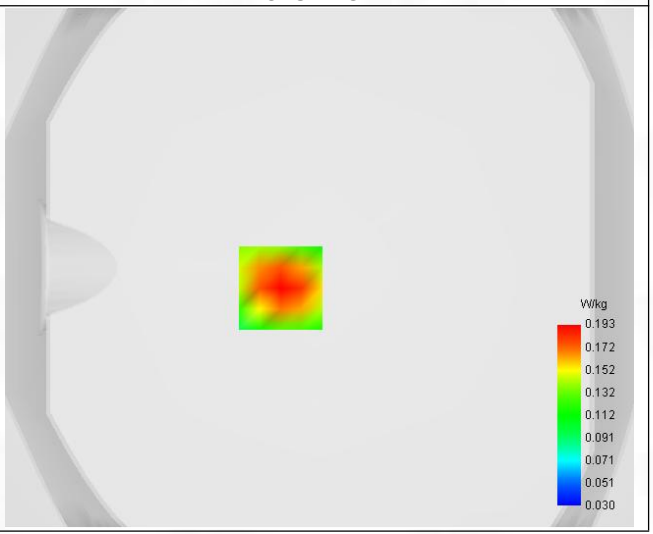
A. Experimental conditions.

Probe	SN 04/22 EPGO365
ConvF	1.96
Area Scan	surf_sam_plan.txt
Zoom Scan	5x5x7,dx=8mm dy=8mm dz=5mm,Complete
Phantom	Validation plane
Device Position	Body
Band	LTE band 2
Channels	Middle (18900)
Signal	LTE FDD
Cell Bandwidth	20 Mhz
Modulation	SC-OFDM - QPSK
RB offset	0
RB size	1

B. Permitivity

Frequency (MHz)	1880.000
Relative permitivity (real part)	41.506
Relative permitivity (imaginary part)	13.522
Conductivity (S/m)	1.402

C. SAR Surface and Volume

SURFACE SAR	VOLUME SAR
	

Maximum location: X=-15.00, Y=-8.00 ; SAR Peak: 0.28 W/kg

D. SAR 1g & 10g

SAR 10g (W/Kg)	0.121
SAR 1g (W/Kg)	0.192
Variation (%)	-1.550
Horizontal validation criteria: minimum distance (mm)	0.000000
Vertical validation criteria: SAR ratio M2/M1 (%)	0.000000

E. Z Axis Scan

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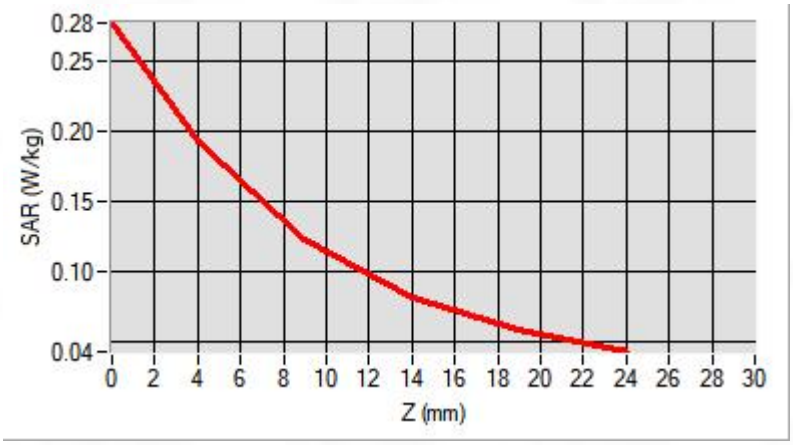
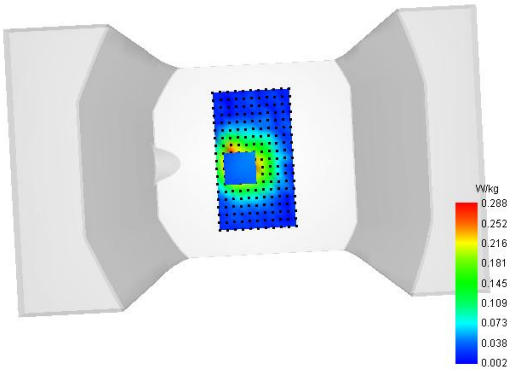
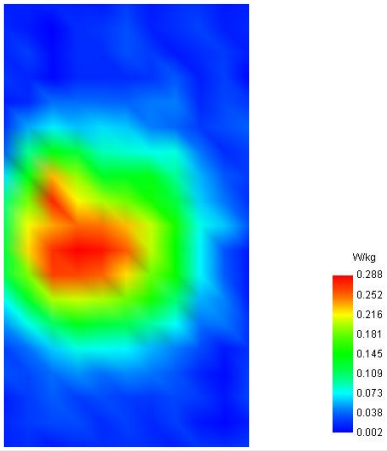
Z (mm)	0.00	4.00	9.00	14.00	19.00
SAR (W/Kg)	0.278	0.193	0.122	0.081	0.058



F. 3D Image

3D screen shot	Hot spot position
	

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4-Extremity with back position in dist. 0mm Channel 20050 in LTE band 4

SAR Measurement at LTE band 4 (Body, Validation Plane)

Date of measurement: 25/9/2023

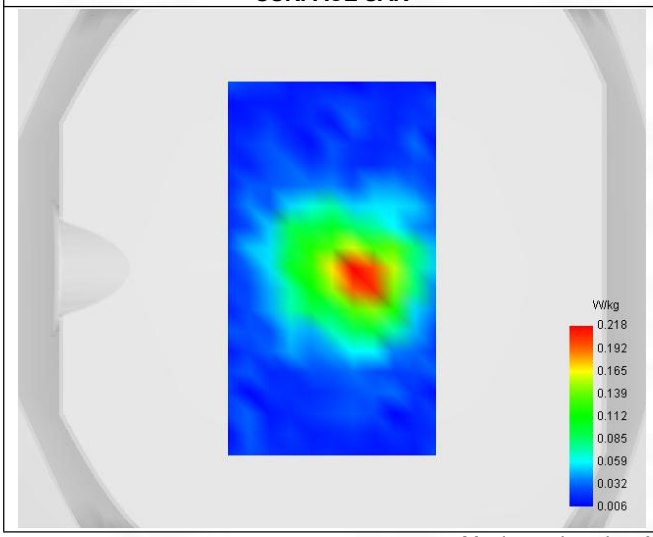
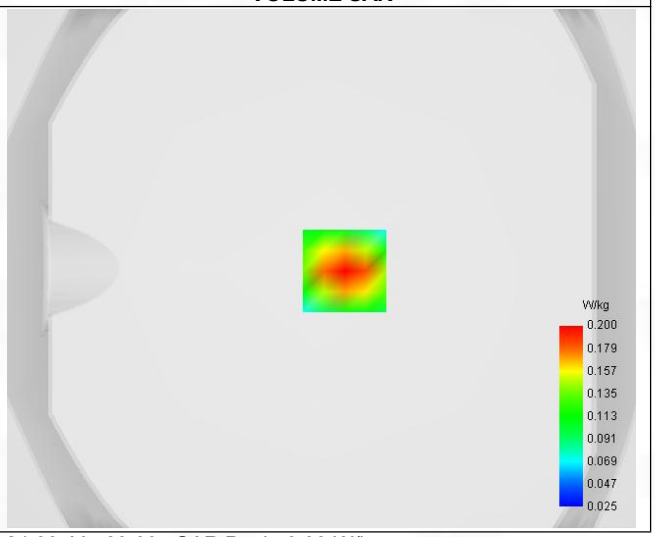
A. Experimental conditions.

Probe	SN 04/22 EPGO365
ConvF	1.68
Area Scan	surf_sam_plan.txt
Zoom Scan	5x5x7,dx=8mm dy=8mm dz=5mm,Complete
Phantom	Validation plane
Device Position	Body
Band	LTE band 4
Channels	Lower (20050)
Signal	LTE FDD
Cell Bandwidth	20 Mhz
Modulation	SC-OFDM - QPSK
RB offset	0
RB size	1

B. Permitivity

Frequency (MHz)	1720.000
Relative permitivity (real part)	41.673
Relative permitivity (imaginary part)	14.538
Conductivity (S/m)	1.329

C. SAR Surface and Volume

SURFACE SAR	VOLUME SAR
	

Maximum location: X=24.00, Y=-63.00 ; SAR Peak: 0.03 W/kg

D. SAR 1g & 10g

SAR 10g (W/Kg)	0.101
SAR 1g (W/Kg)	0.185
Variation (%)	-1.300
Horizontal validation criteria: minimum distance (mm)	0.000000
Vertical validation criteria: SAR ratio M2/M1 (%)	0.000000

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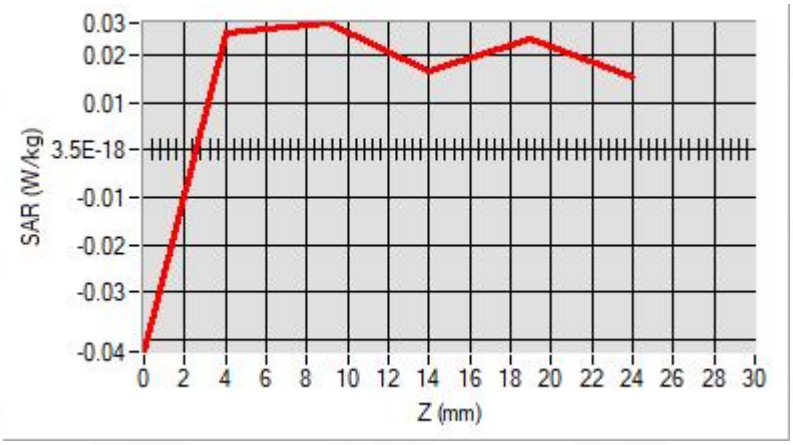
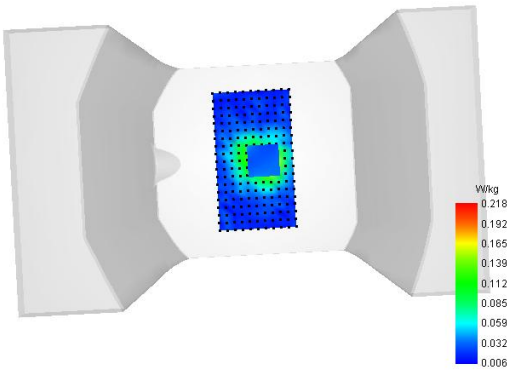
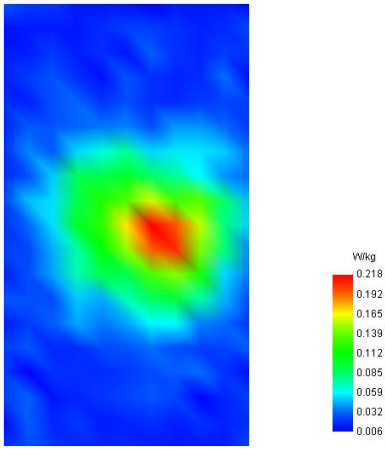
E. Z Axis Scan

Z (mm)	0.00	4.00	9.00	14.00	19.00
SAR (W/Kg)	-0.043	0.025	0.027	0.017	0.023



F. 3D Image

3D screen shot	Hot spot position
	

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5-Extremity with back position in dist. 0mm Channel 20450 in LTE Band 5

SAR Measurement at LTE band 5 (Body, Validation Plane)

Date of measurement: 25/9/2023

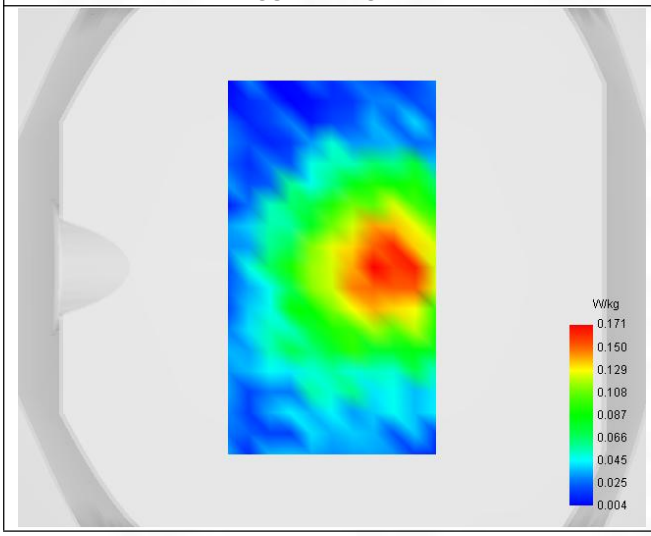
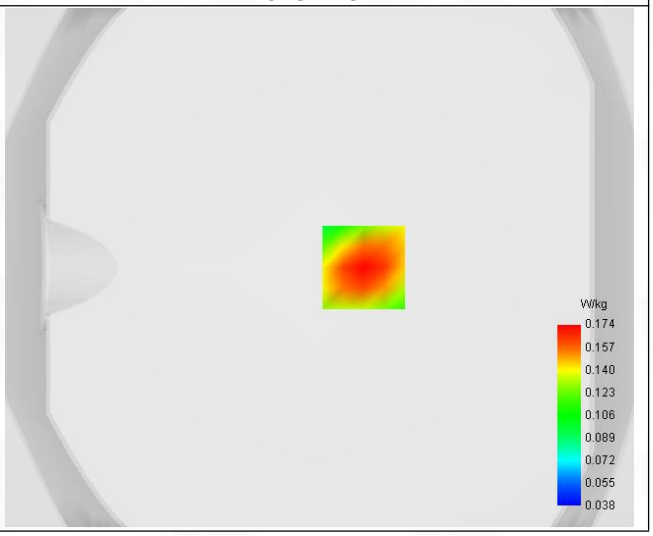
A. Experimental conditions.

Probe	SN 04/22 EPGO365
ConvF	1.68
Area Scan	surf_sam_plan.txt
Zoom Scan	5x5x7,dx=8mm dy=8mm dz=5mm,Complete
Phantom	Validation plane
Device Position	Body
Band	LTE band 5
Channels	Lower (20450)
Signal	LTE FDD
Cell Bandwidth	10 Mhz
Modulation	SC-OFDM - QPSK
RB offset	0
RB size	1

B. Permitivity

Frequency (MHz)	832.090
Relative permitivity (real part)	43.262
Relative permitivity (imaginary part)	19.557
Conductivity (S/m)	0.870

C. SAR Surface and Volume

SURFACE SAR	VOLUME SAR
	

Maximum location: X=17.00, Y=0.00 ; SAR Peak: 0.22 W/kg

D. SAR 1g & 10g

SAR 10g (W/Kg)	0.127
SAR 1g (W/Kg)	0.179
Variation (%)	-3.010
Horizontal validation criteria: minimum distance (mm)	0.000000
Vertical validation criteria: SAR ratio M2/M1 (%)	0.000000

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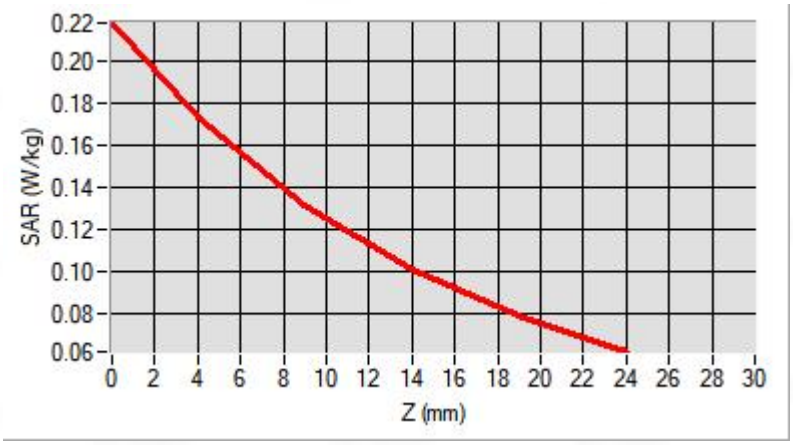
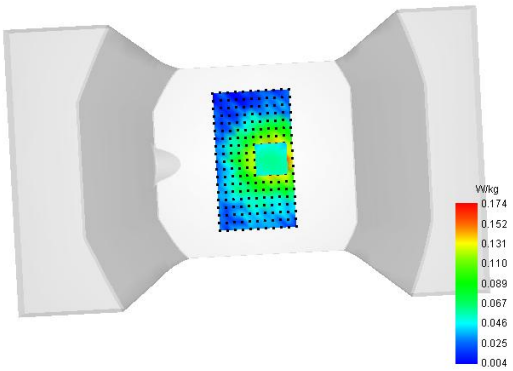
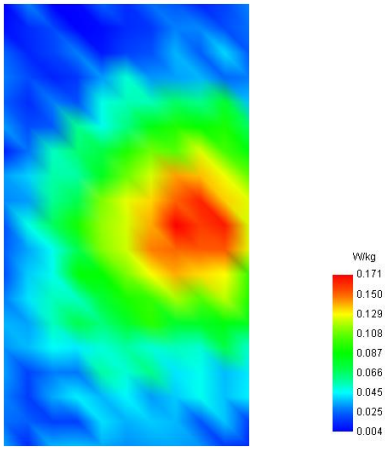
E. Z Axis Scan

Z (mm)	0.00	4.00	9.00	14.00	19.00
SAR (W/Kg)	0.218	0.174	0.131	0.101	0.079



F. 3D Image

3D screen shot	Hot spot position
	

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6-Extremity with back position in dist. 0mm Channel 21100 in LTE Band 7

SAR Measurement at LTE band 7 (Body, Validation Plane)

Date of measurement: 25/9/2023

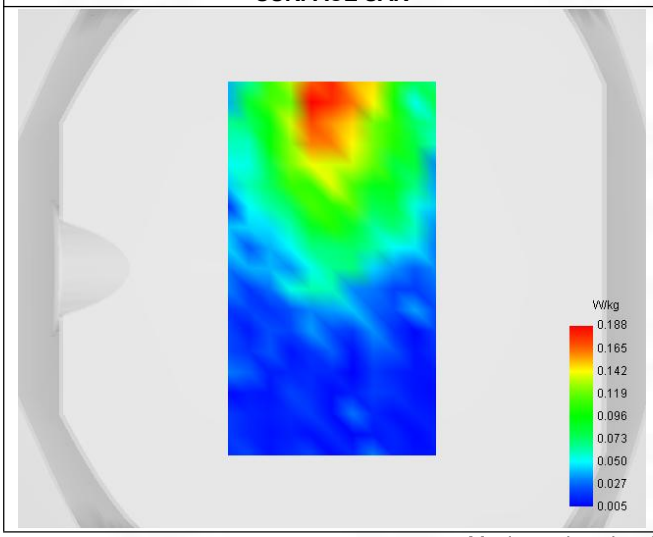
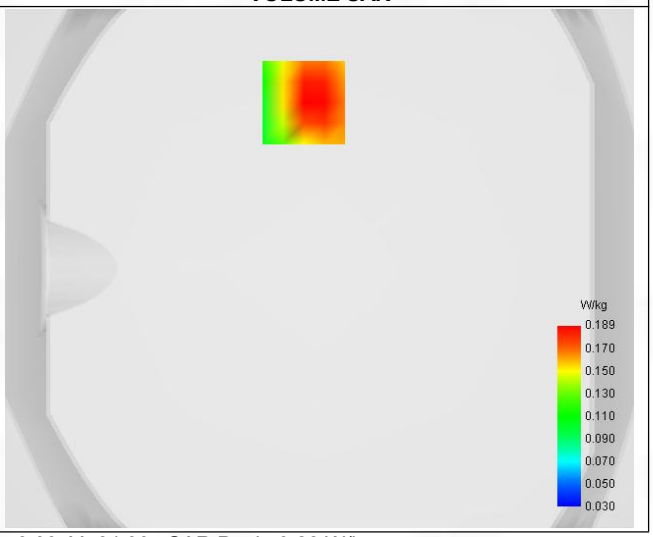
A. Experimental conditions.

Probe	SN 04/22 EPGO365
ConvF	2.36
Area Scan	surf_sam_plan.txt
Zoom Scan	5x5x7,dx=8mm dy=8mm dz=5mm,Complete
Phantom	Validation plane
Device Position	Body
Band	LTE band 7
Channels	Middle (21100)
Signal	LTE FDD
Cell Bandwidth	20 Mhz
Modulation	SC-OFDM - QPSK
RB offset	99
RB size	1

B. Permitivity

Frequency (MHz)	2535.910
Relative permitivity (real part)	41.275
Relative permitivity (imaginary part)	12.968
Conductivity (S/m)	1.902

C. SAR Surface and Volume

SURFACE SAR	VOLUME SAR
	

Maximum location: X=-6.00, Y=64.00 ; SAR Peak: 0.28 W/kg

D. SAR 1g & 10g

SAR 10g (W/Kg)	0.081
SAR 1g (W/Kg)	0.169
Variation (%)	2.050
Horizontal validation criteria: minimum distance (mm)	0.000000
Vertical validation criteria: SAR ratio M2/M1 (%)	0.000000

E. Z Axis Scan

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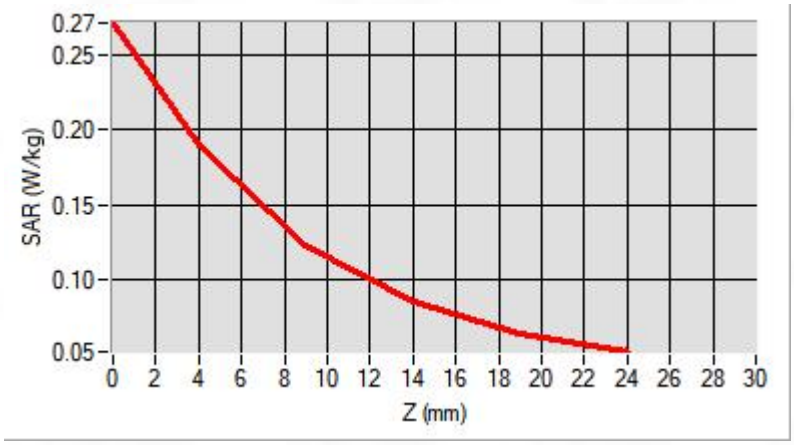
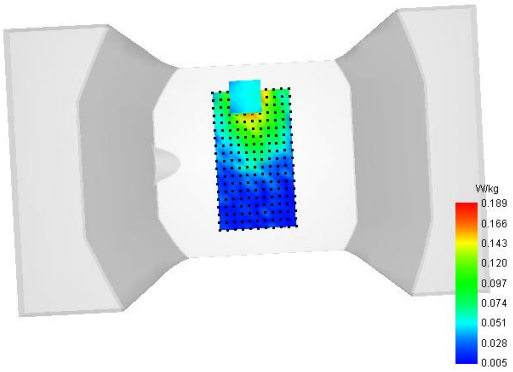
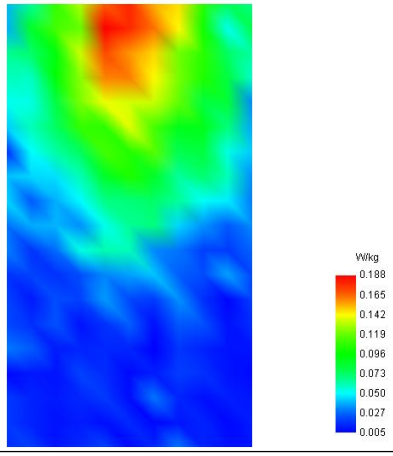
Z (mm)	0.00	4.00	9.00	14.00	19.00
SAR (W/Kg)	0.272	0.189	0.123	0.084	0.064



F. 3D Image

3D screen shot	Hot spot position
	

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7-Extremity with back position in dist. 0mm Channel 23060 in LTE Band 12

SAR Measurement at LTE band 12 (Body, Validation Plane)

Date of measurement: 25/9/2023

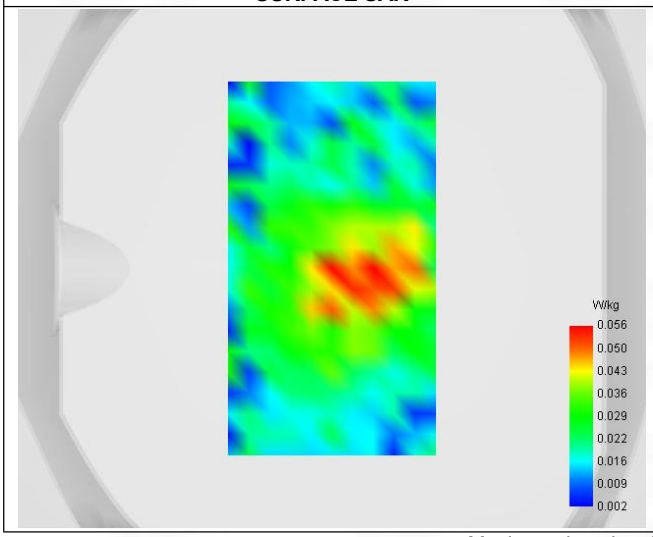
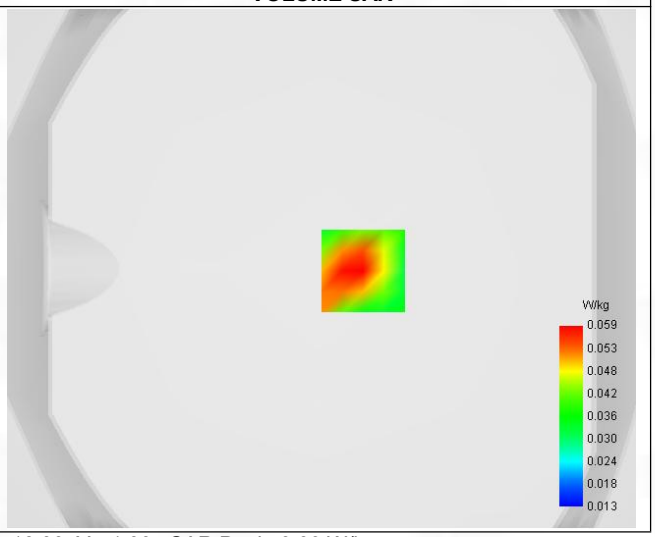
A. Experimental conditions.

Probe	SN 04/22 EPGO365
ConvF	1.65
Area Scan	surf_sam_plan.txt
Zoom Scan	5x5x7,dx=8mm dy=8mm dz=5mm,Complete
Phantom	Validation plane
Device Position	Body
Band	LTE band 12
Channels	Lower (23060)
Signal	LTE FDD
Cell Bandwidth	10 Mhz
Modulation	SC-OFDM - QPSK
RB offset	25
RB size	1

B. Permitivity

Frequency (MHz)	704.090
Relative permitivity (real part)	43.804
Relative permitivity (imaginary part)	22.524
Conductivity (S/m)	0.855

C. SAR Surface and Volume

SURFACE SAR	VOLUME SAR
	

Maximum location: X=16.00, Y=-1.00 ; SAR Peak: 0.09 W/kg

D. SAR 1g & 10g

SAR 10g (W/Kg)	0.047
SAR 1g (W/Kg)	0.062
Variation (%)	-1.850
Horizontal validation criteria: minimum distance (mm)	0.000000
Vertical validation criteria: SAR ratio M2/M1 (%)	0.000000

E. Z Axis Scan

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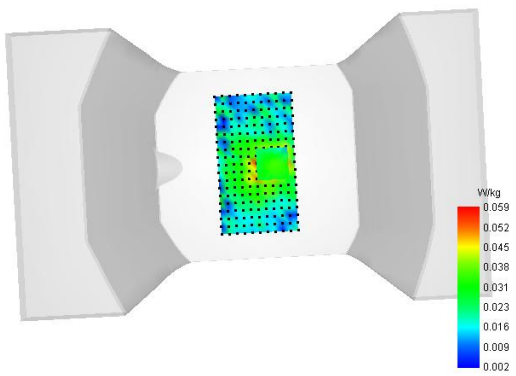
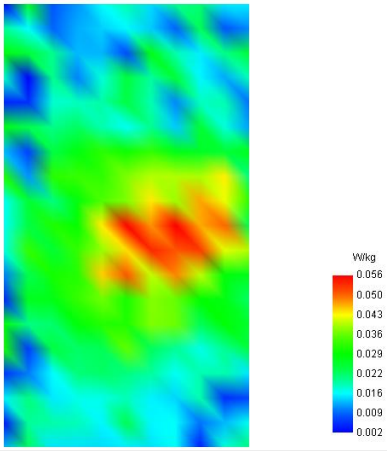
Z (mm)	0.00	4.00	9.00	14.00	19.00
SAR (W/Kg)	0.090	0.059	0.038	0.030	0.031

F. 3D Image

3D screen shot	Hot spot position
	

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8-Extremity with back position in dist. 0mm Channel 23780 in LTE Band 17

SAR Measurement at LTE band 17 (Body, Validation Plane)

Date of measurement: 25/9/2023

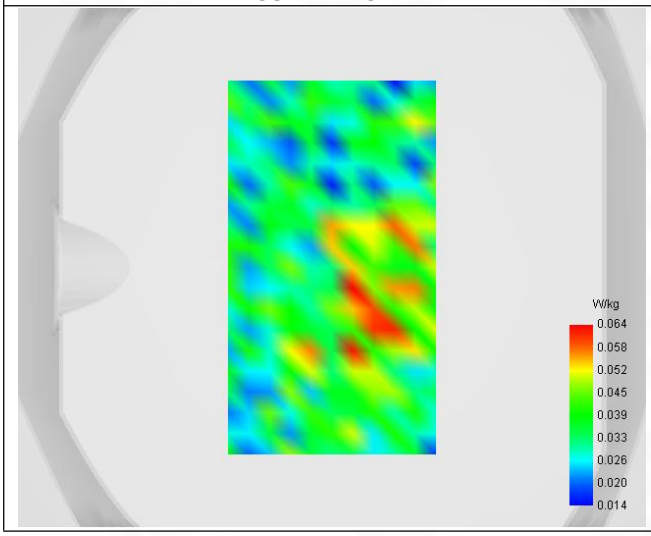
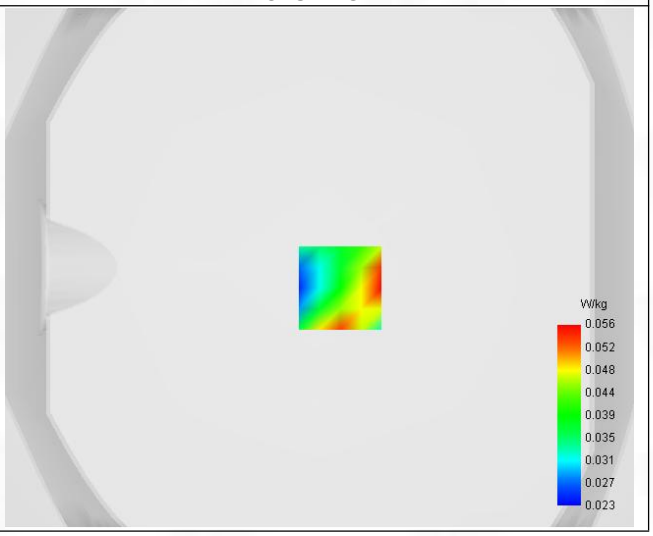
A. Experimental conditions.

Probe	SN 04/22 EPGO365
ConvF	1.65
Area Scan	surf_sam_plan.txt
Zoom Scan	5x5x7,dx=8mm dy=8mm dz=5mm,Complete
Phantom	Validation plane
Device Position	Body
Band	LTE band 17
Channels	Lower (23780)
Signal	LTE FDD
Cell Bandwidth	10 Mhz
Modulation	SC-OFDM - QPSK
RB offset	49
RB size	1

B. Permitivity

Frequency (MHz)	713.410
Relative permitivity (real part)	43.765
Relative permitivity (imaginary part)	22.308
Conductivity (S/m)	0.856

C. SAR Surface and Volume

SURFACE SAR	VOLUME SAR
	

Maximum location: X=8.00, Y=-8.00 ; SAR Peak: 0.08 W/kg

D. SAR 1g & 10g

SAR 10g (W/Kg)	0.040
SAR 1g (W/Kg)	0.054
Variation (%)	-1.370
Horizontal validation criteria: minimum distance (mm)	0.000000
Vertical validation criteria: SAR ratio M2/M1 (%)	0.000000

E. Z Axis Scan

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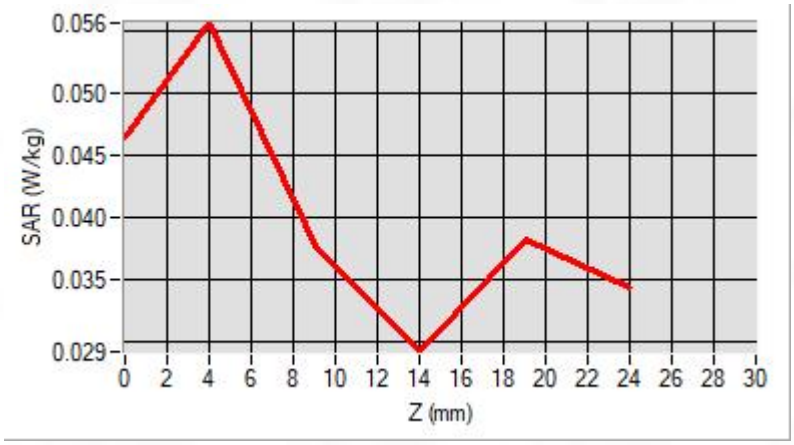
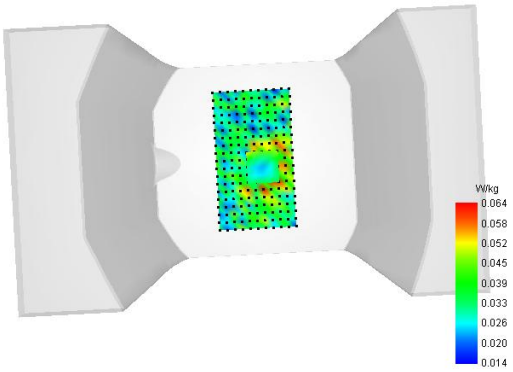
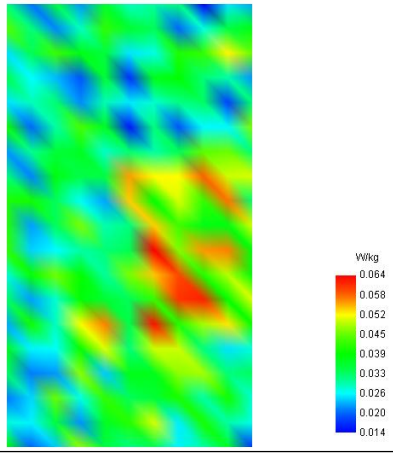
Z (mm)	0.00	4.00	9.00	14.00	19.00
SAR (W/Kg)	0.047	0.056	0.038	0.029	0.038



F. 3D Image

3D screen shot	Hot spot position
	

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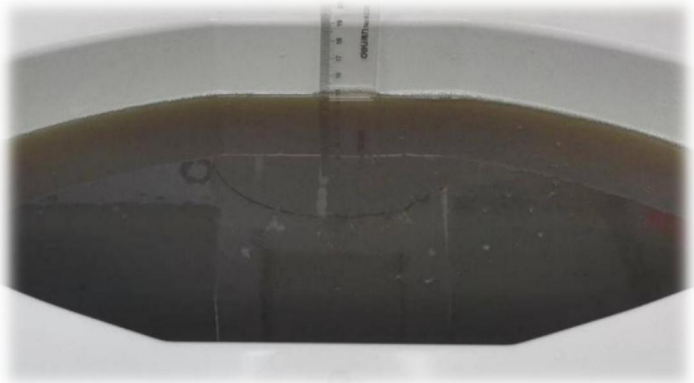
ANNEX D SAR Test Setup Photos

Reference Photo: simulation liquid depth 15cm

Reference Photos
Extremity Back（dist. 0mm）

ANNEX E EUT External and Internal Photos

Please refer to RF Report.

ANNEX F Calibration Information

Please refer to the document “Calibration.pdf”.

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